

Data Handling Processor Performance Test Results

Tetsuichi Kishishita, Bonn University
DEPFET PXD ASIC Design Review, October 27-28, 2014

- Verification results from prototype blocks (DHPT 0.1)
 - PLL & high speed serial link driver
 - Analog blocks (bias generator, temp. sensor)

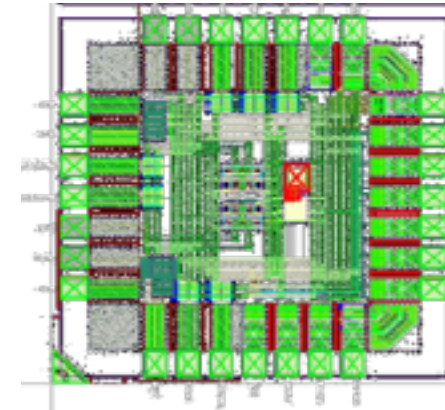
- DHPT 1.0 performance
 - Verification results
 - Known issues & mitigation strategies

DHPT 0.1 Prototype Chip

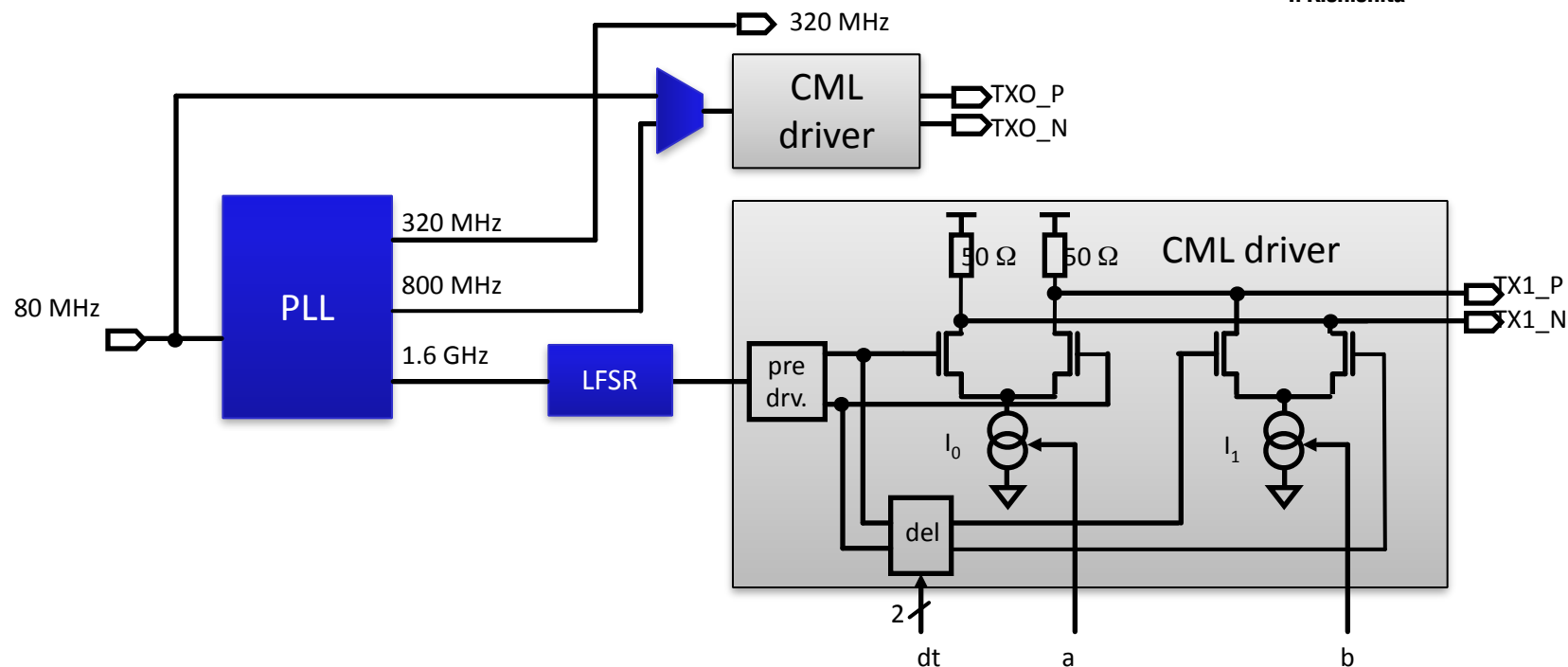
PLL & GBIT DRIVER

DHPT 0.1 - PLL & Gbit Driver

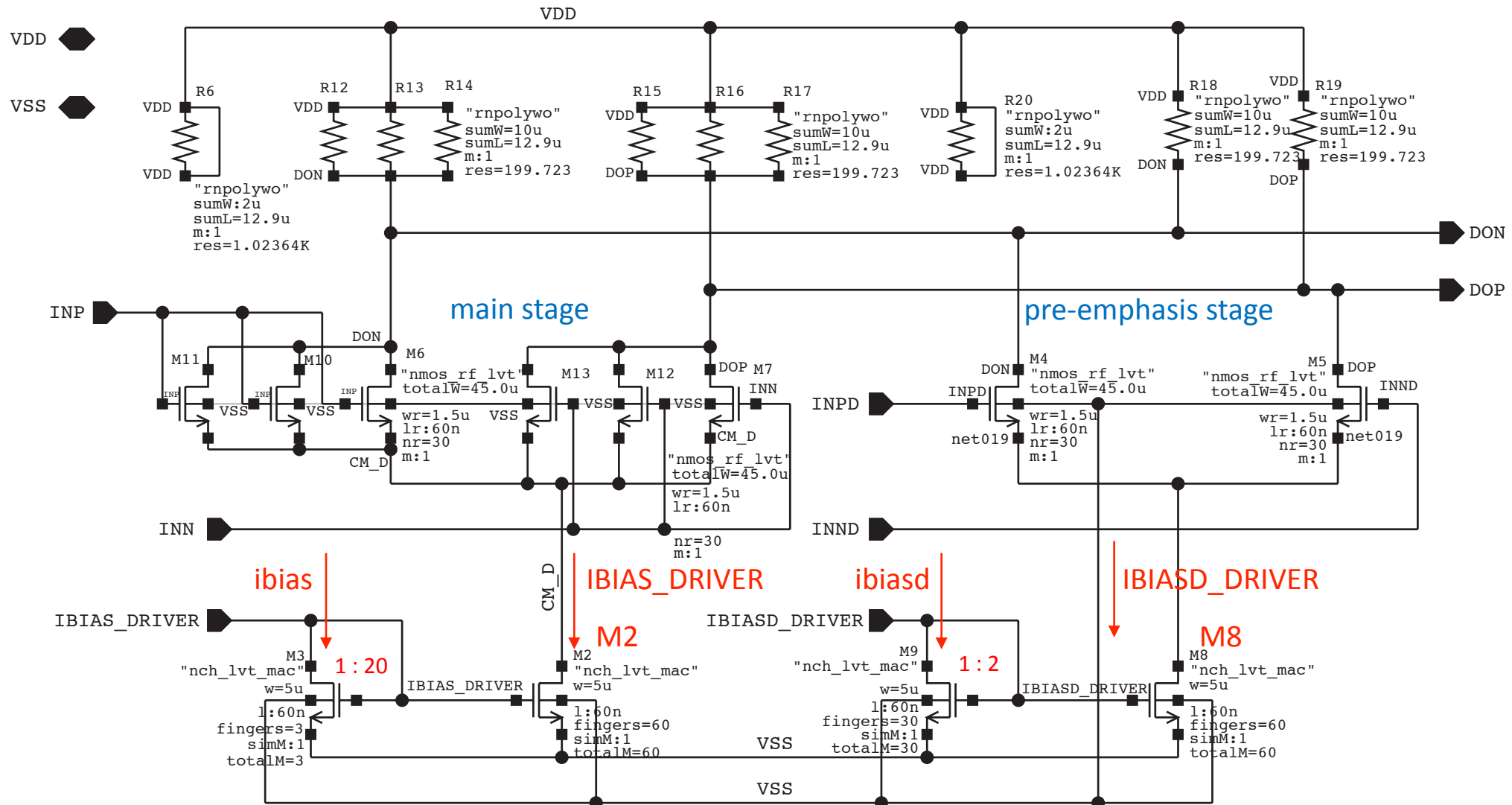
- PLL
 - 80 MHz reference clock
 - 1.6 GHz, 800MHz & 320 MHz outputs
- Pseudo random bit sequence generator
 - 8 bit LFSR
- CML link driver with programmable pre-emphasis
 - Two differential pairs with adj. bias currents (tap weights a, b)
 - Programmable delay dt



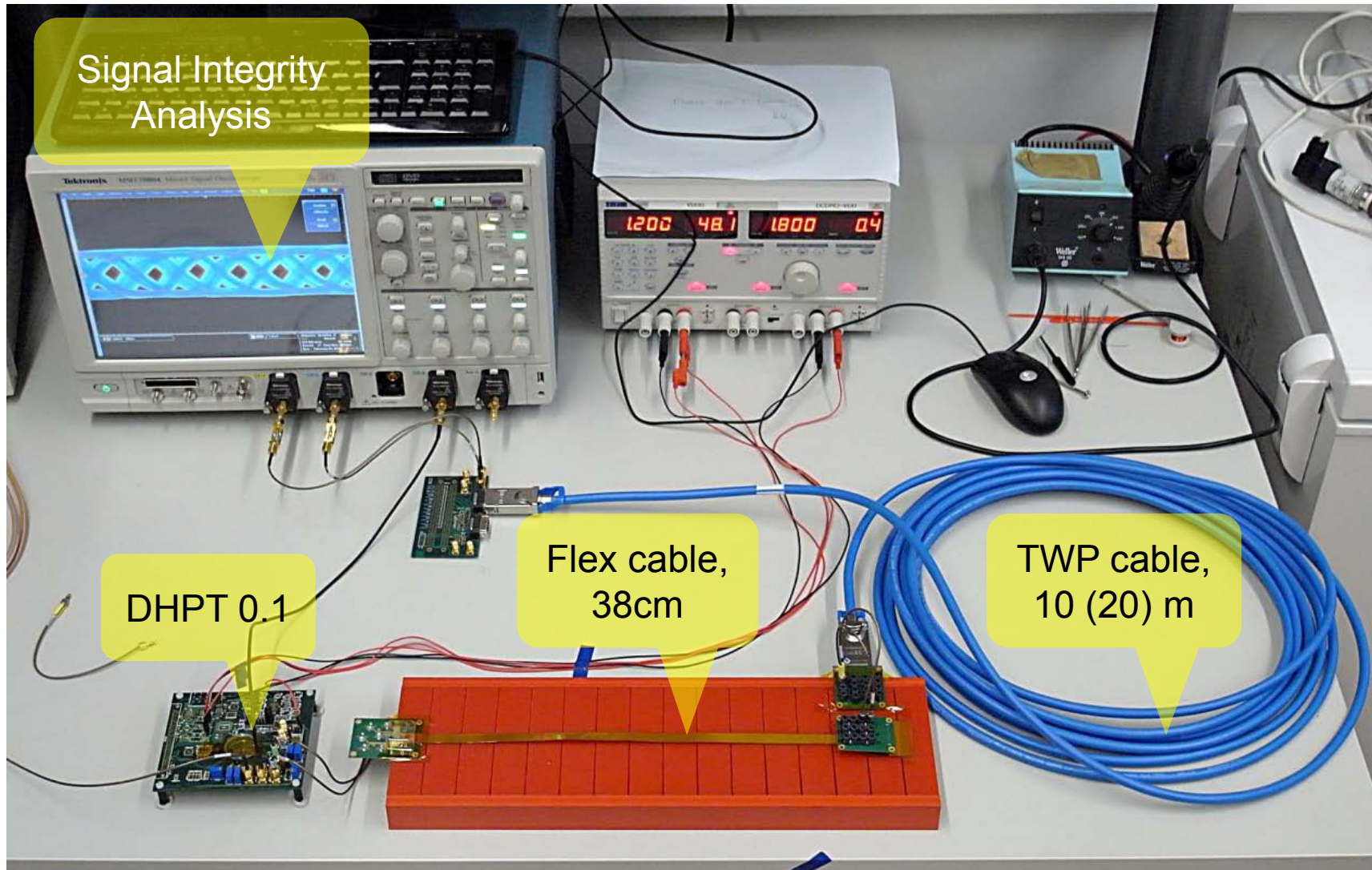
PLL_CML Test Chip,
T. Kishishita



Driver Schematic

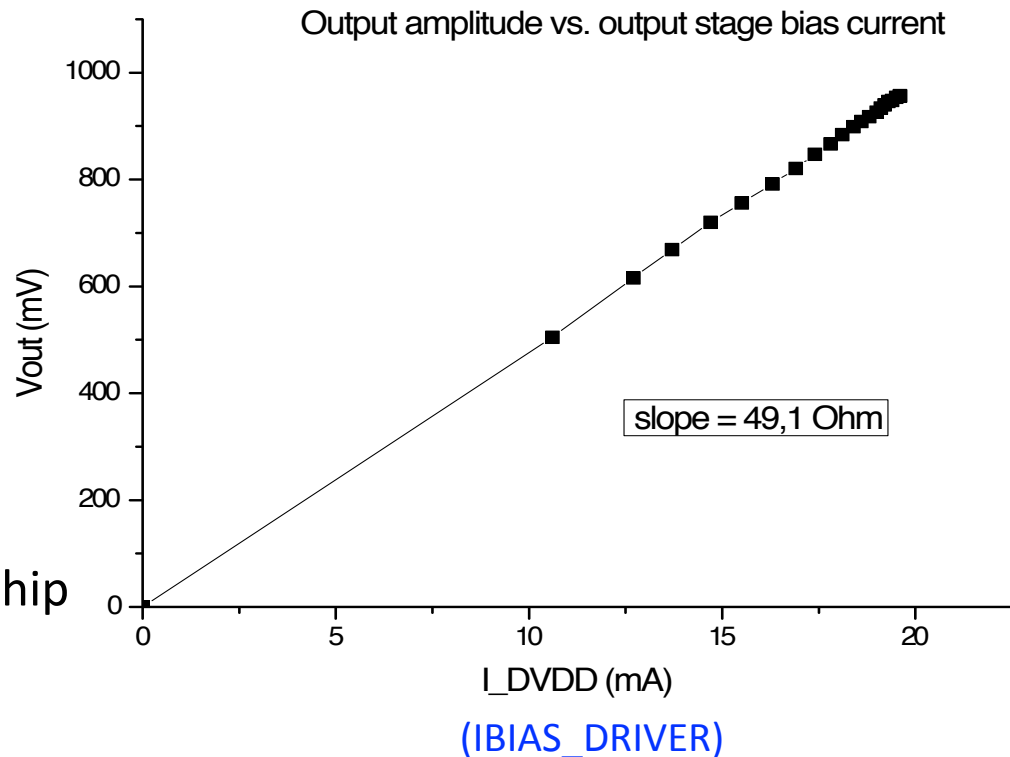


DHPT 0.1 – Test setup



Differential Output Amplitude

- Linear function of bias current (IBIAS_DRIVER)
- $IBIAS_DRIVER \approx I_DVDD$
- Pre-emphasis off (IBIASD_Driver = 0)
- Effective output resistance: 49.1 Ohm
- DC output resistance: 55 Ohm
- → ~3.5 Ohm Series resistance (chip wiring, bond wire, PCB trace)

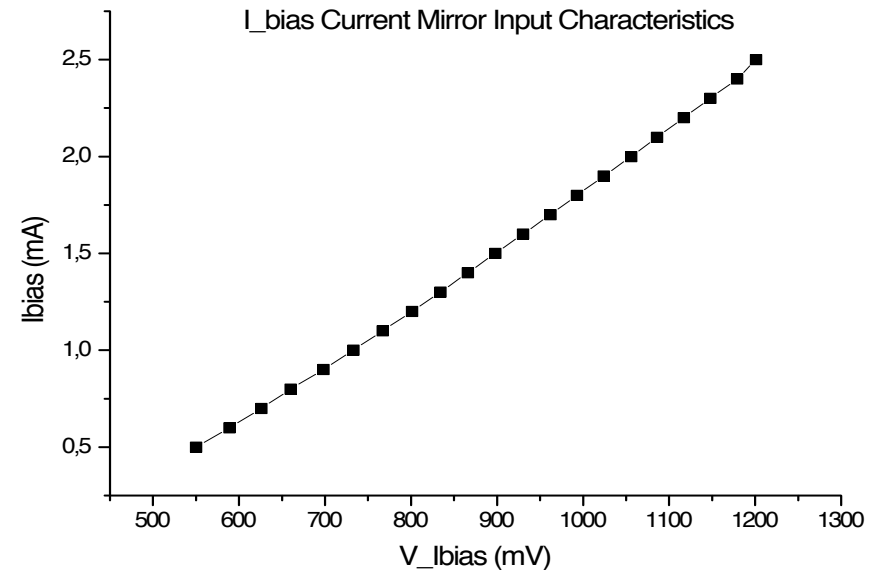
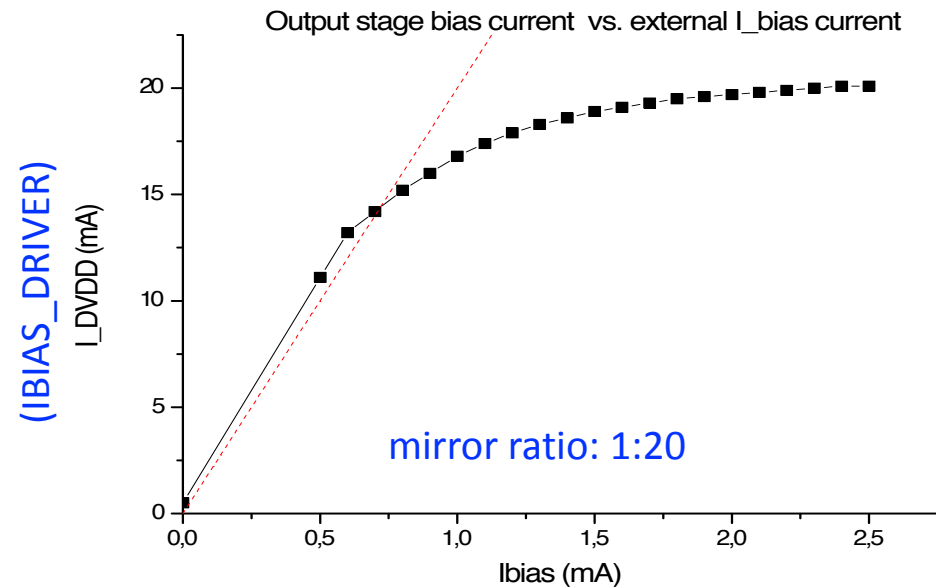


→ Output resistance Ok

Main Output Current Mirror

- IBIAS_DRIVER current mirror
- Design value
 $IBIAS_DRIVER/I_{bias} = 20$
- Non-linear for $I_{bias} > 0.7\text{mA}$
→ M2 not saturated?
- Drive current limited to 20 mA
→ $V_{out_max} = 957\text{ mV}$

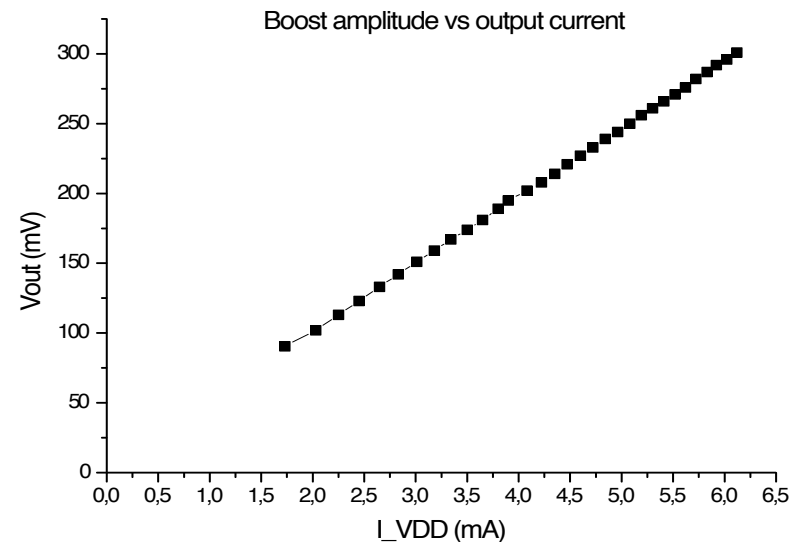
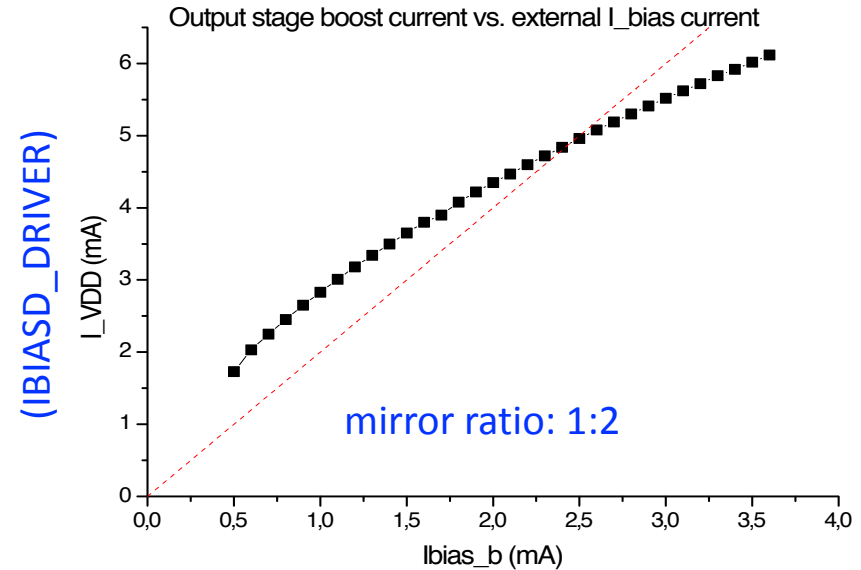
→ Limited by current sink (M2) or switches M0/M1 (too high on resistance)?



Boost Output Current Mirror

- IBIASD_DRIVER current mirror
- Design value
 $IBIASD_DRIVER/I_{biasd} = 2$
- Fair linearity
- Drive current limited to 6.12 mA
→ $V_{boost_max} \sim 300mV$

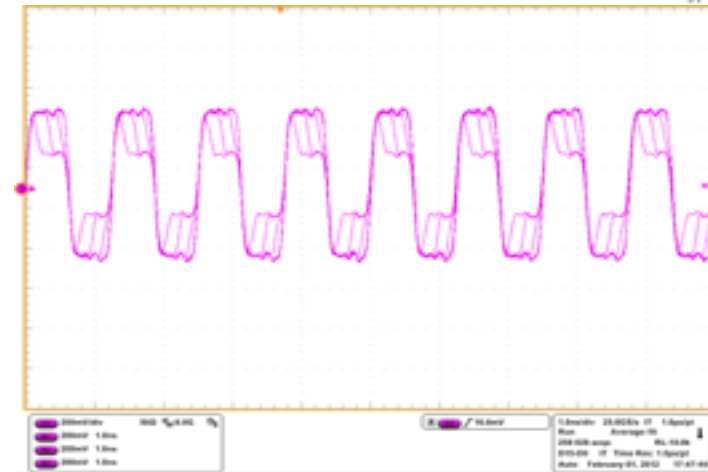
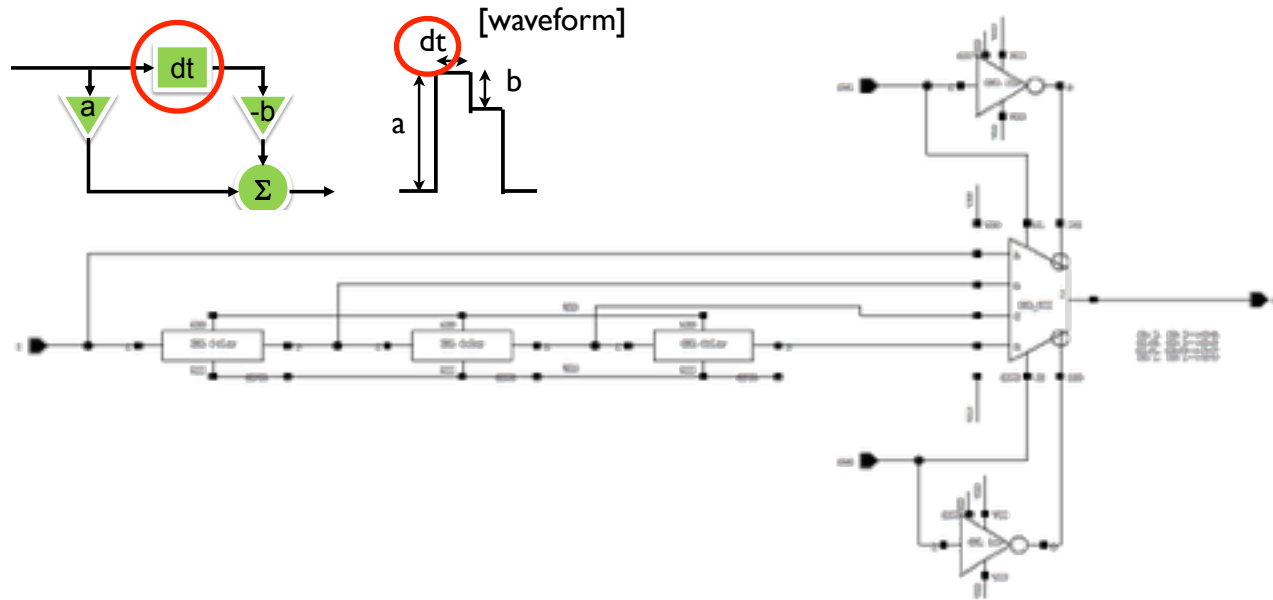
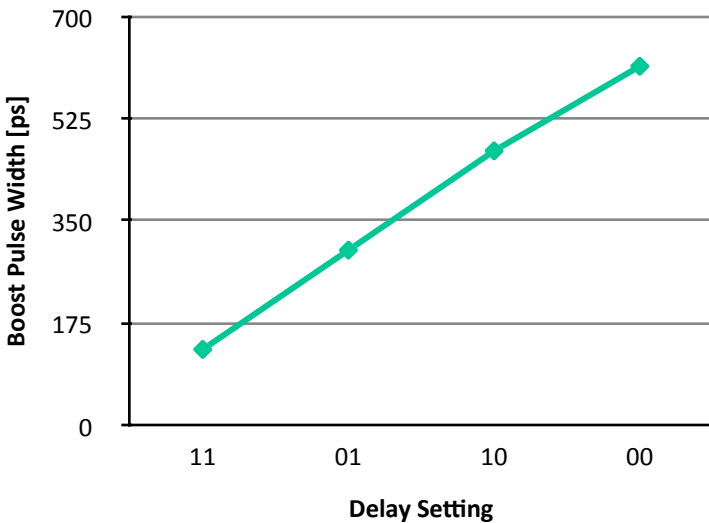
→ Make boost current sink M8 stronger



Delay Settings

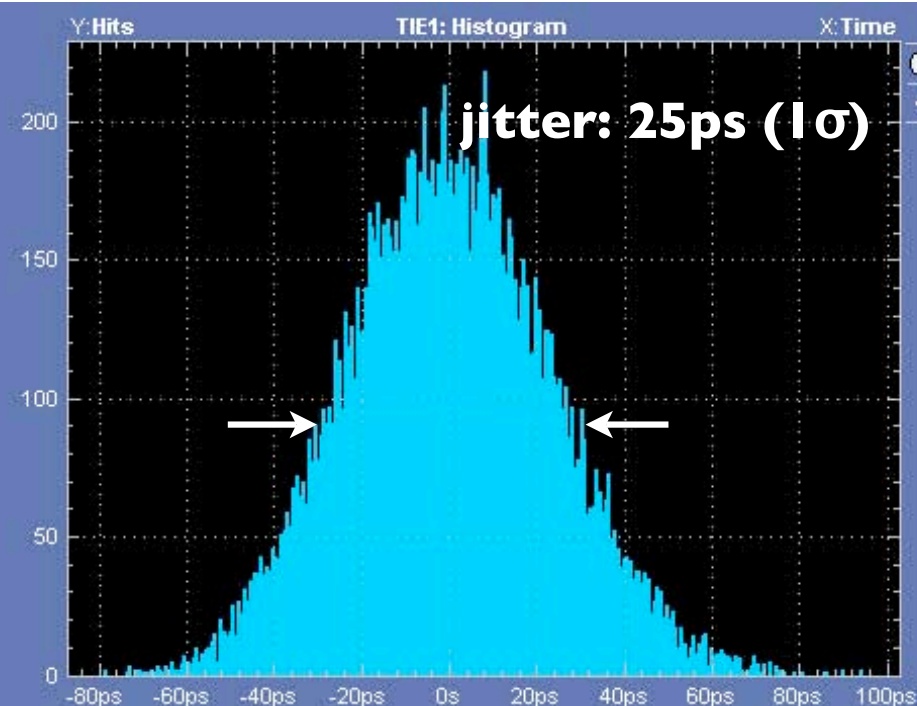
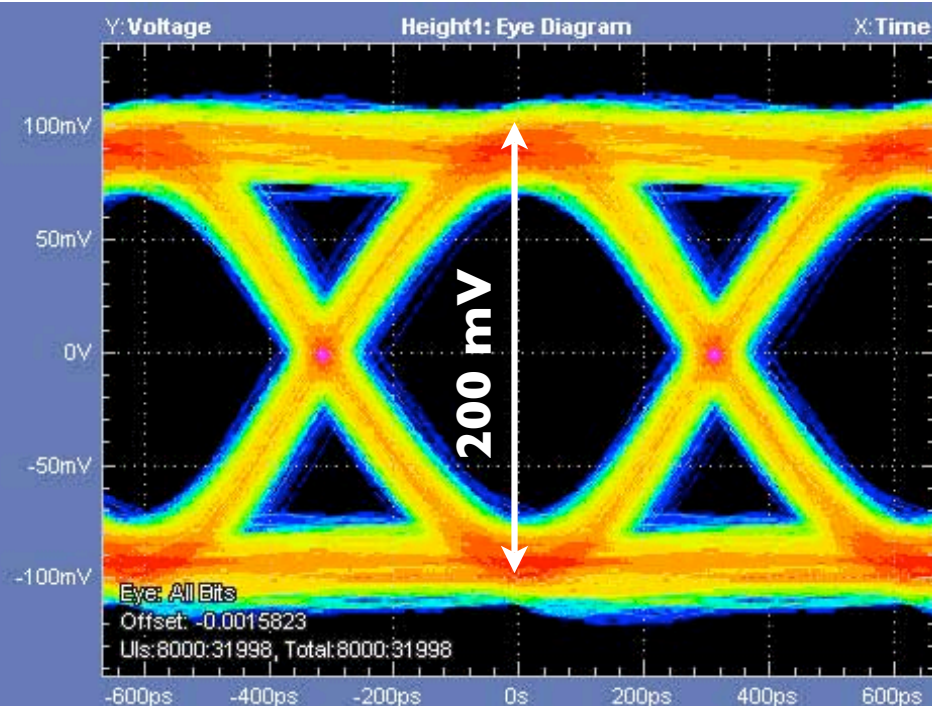
Setting SW[1:0]	Pulse Width [ps]
11	130
01	300
10	470
00	615

→ ~170 ps per delay buffer

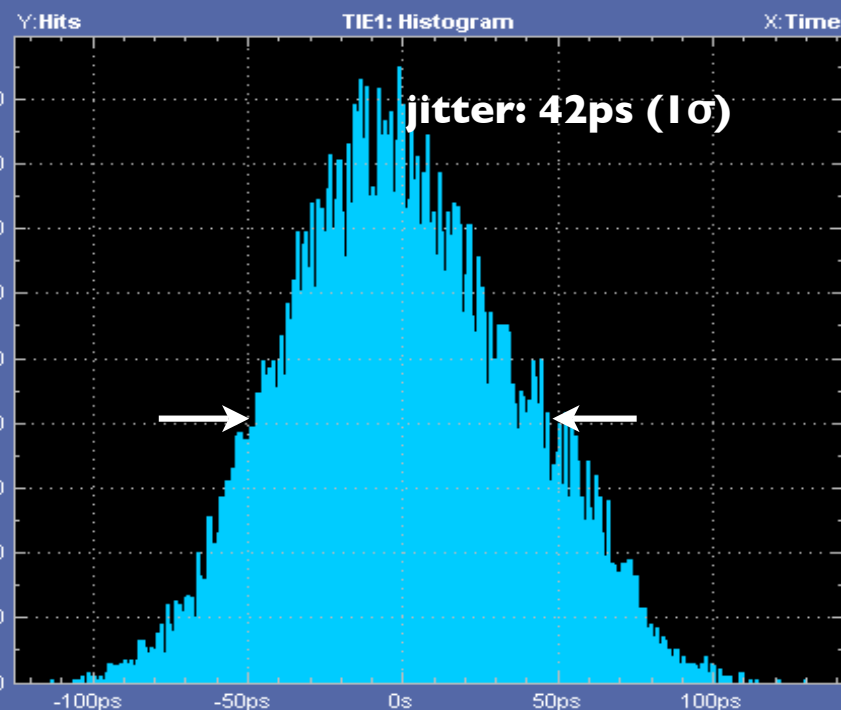
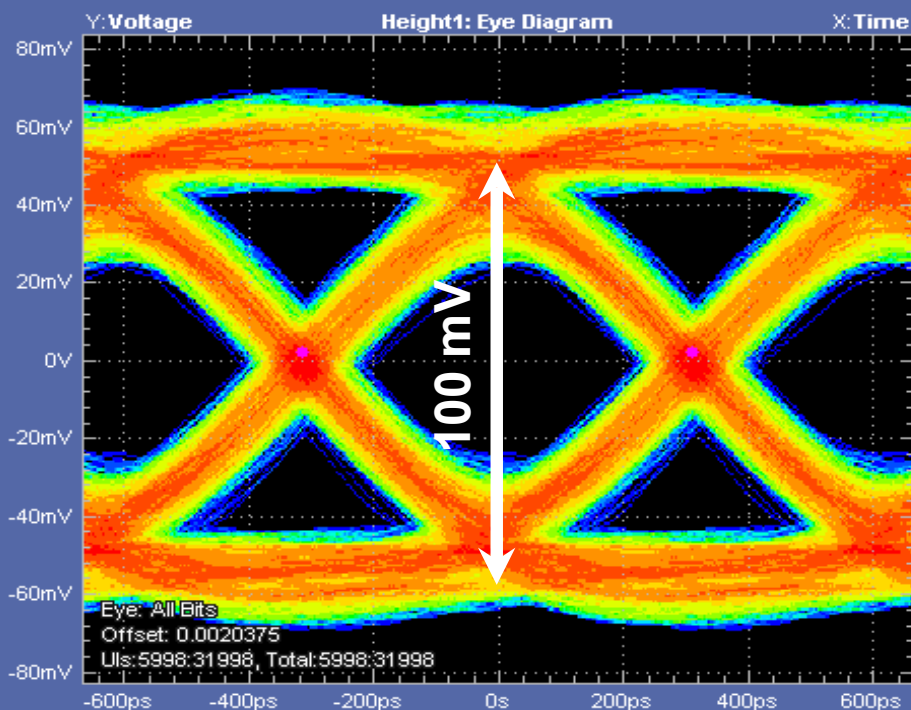


800 MHz clock, different delay settings

- 1.6 Gbps LFSR-8
- 30 cm kapton cable
+ **10m** AWG26
twisted pair cable



- 1.6 Gbps LFSR-8
- 30 cm kapton cable
+ **20m** AWG26
twisted pair cable

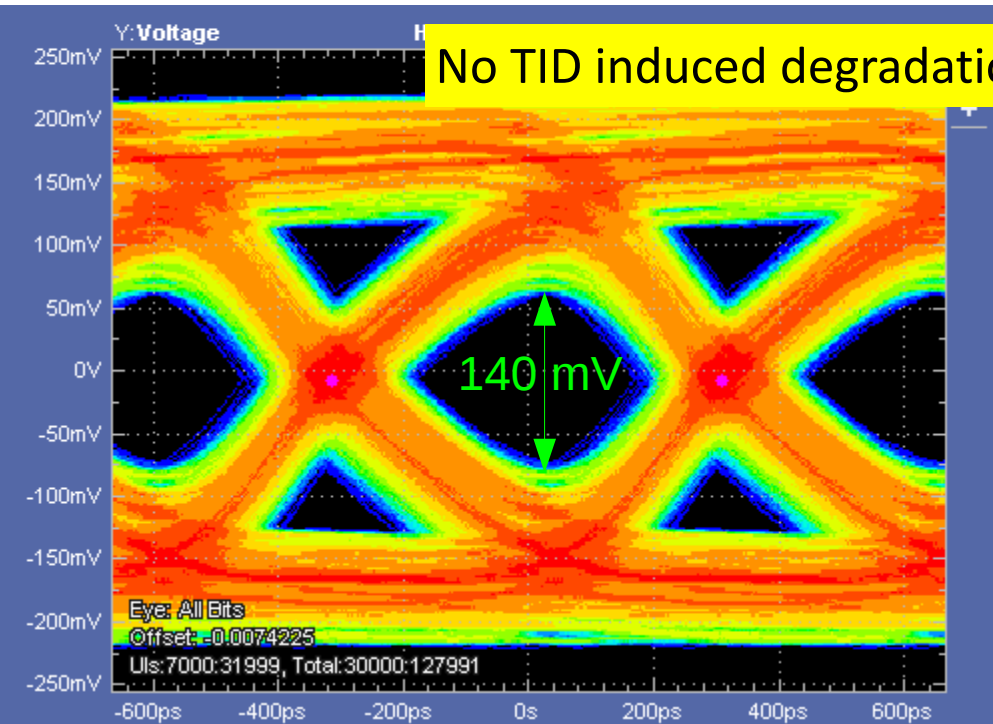


DHPT 0.1 X-ray Irradiation

- TSMC 65nm TID tolerance:
 - V_{THR} shift (wide pMOS and nMOS only)
 - PLL + Gbit link performance (with 15 m cable)
- Up to 100 Mrad (60keV X-ray tube, Karlsruhe)
- Dose rates: ~ 300 kRad/h (initial) $\rightarrow \sim 2$ Mrad/h (end)
- Annealing after each step: 80°C for 100 min

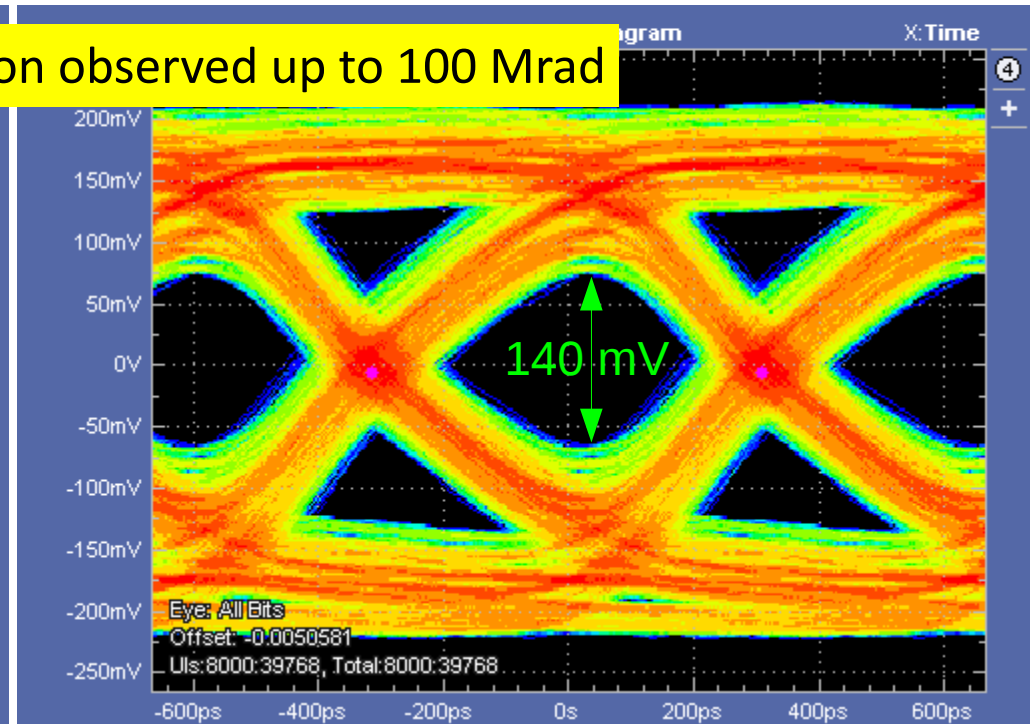
Belle II: 10 Mrad for 5 yr operation

No TID induced degradation observed up to 100 Mrad



Dose = 0 MRad

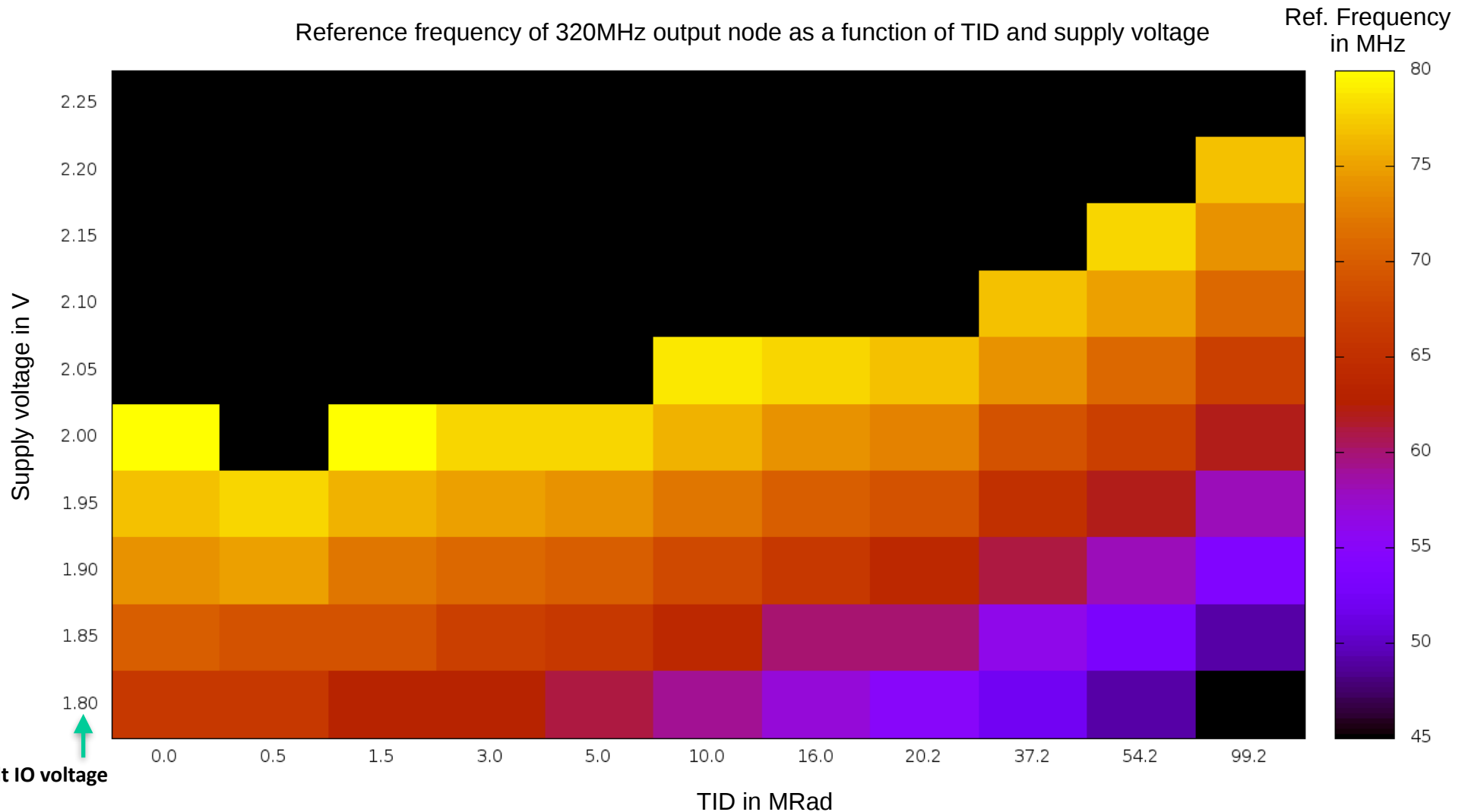
Jitter ~ 51 ps



Dose = 100 MRad

Jitter ~ 54 ps

Reference frequency of 320MHz output node as a function of TID and supply voltage

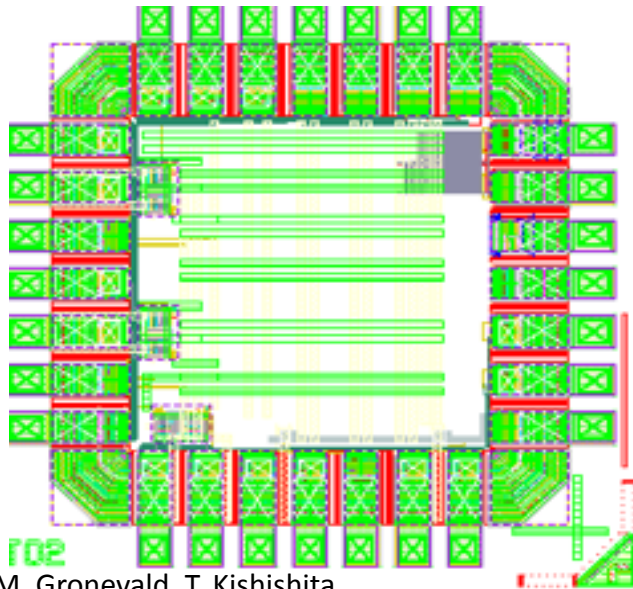


PLL works even after 100 Mrad, slow outputs mainly come from CMOS driver (thick gate oxide).

- Delay settings Ok
 - minimum delay setting (SW[1:0]=11 → 130 ps) shows best eye diagram for long cables
 - Possible optimization: make delay steps a bit smaller (170 ps → 120 ps, 7 → 5 inverter per delay)
- Bias current settings can be optimized
 - Recommended adjustments:
 - Increase main current (+ 5-10mA) → higher signal amplitude
 - Increase boost current (+ 4mA) → higher pre-emphasis level, better damping compensation
 - Current configuration
 - Current sinks: M2 (main bias) same size as M8 (boost bias), but M2 sinks 20 mA and M8 6 mA.
 - Ratio of main and boost switches is 3:1 (Ok)
- Good signal integrity driving 38cm kapton + 20m TWP cable @ 1.6Gbps
- No sensitivity for TID of 100 Mrad

DHPT 0.2

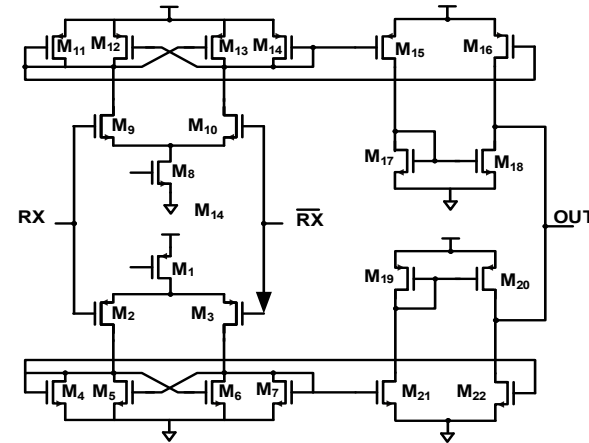
LVDS RX / TX



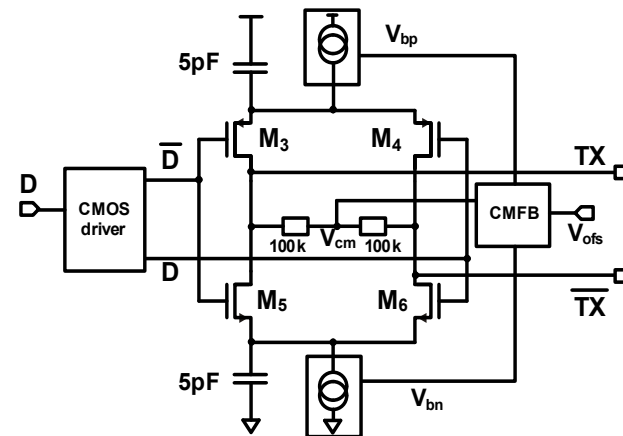
M. Gronevald, T. Kishishita

- LVDS Receiver (1.8/2.5V)
- LVDS Transmitter (1.8/2.5V)
- Level Shifters 1.2V \leftrightarrow 1.8/2.5V
- Custom IO (ARM compatible)

LVDS Receiver

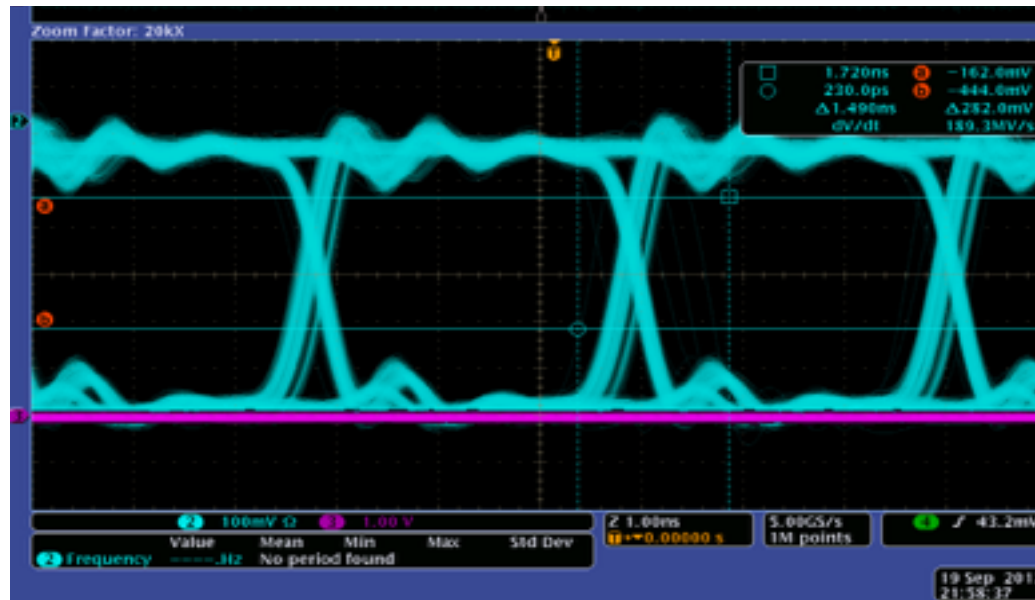


LVDS Driver



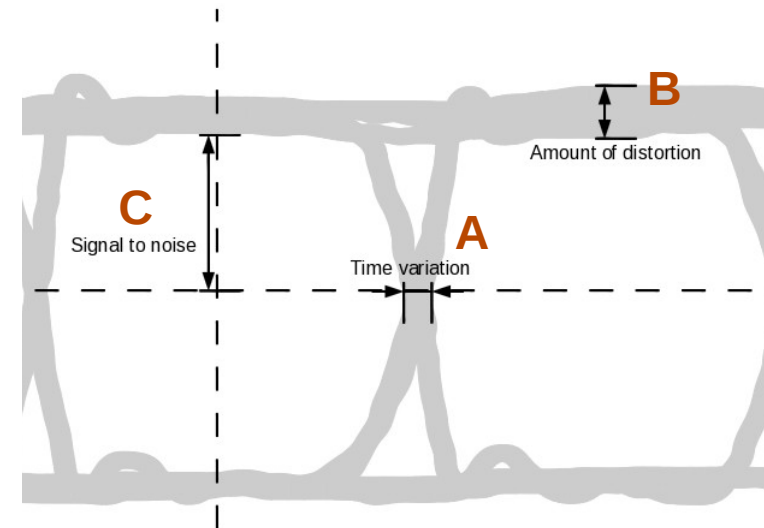
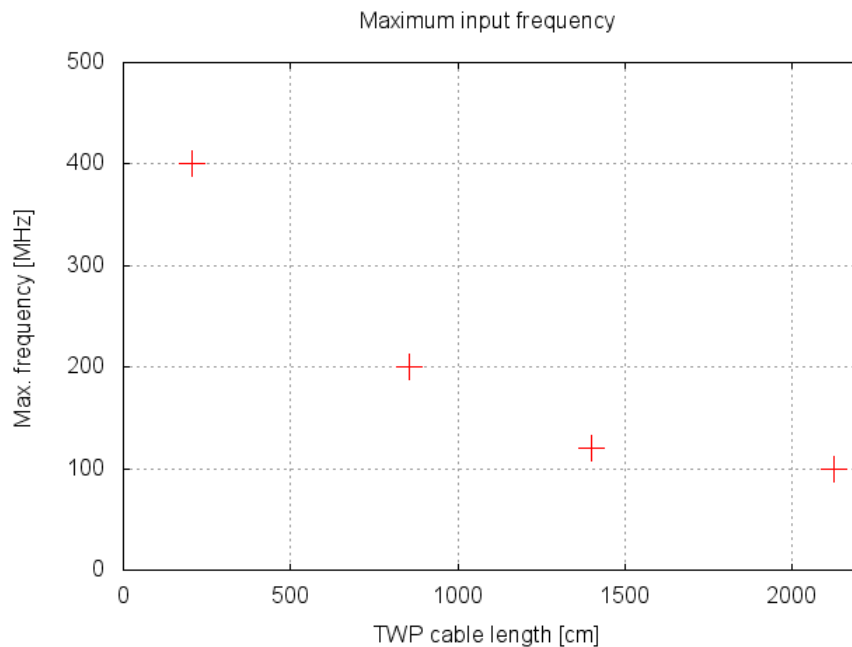
DHPT 0.2 – LVDS TX/RX Results

PRBS (2⁷-1) @ 320MHz - VDD 1.2V/1.8V



Both receiver and transmitter work as expected.

DHPT 0.2 – LVDS TX/RX Results



These values are lower thresholds for the max. frequency!!!

Figure: Measurement for $I_{ref}=150\mu A$ with $V_{DD} = 1.33V$

length [cm]	Max. frequency [MHz]	A [ps]	B [mV]	C [mV]
205	400	1010	212	128
856	200	2260	94	166
1401	120	2940	114	154
2125	100	2920	128	114

DHPT 1.0

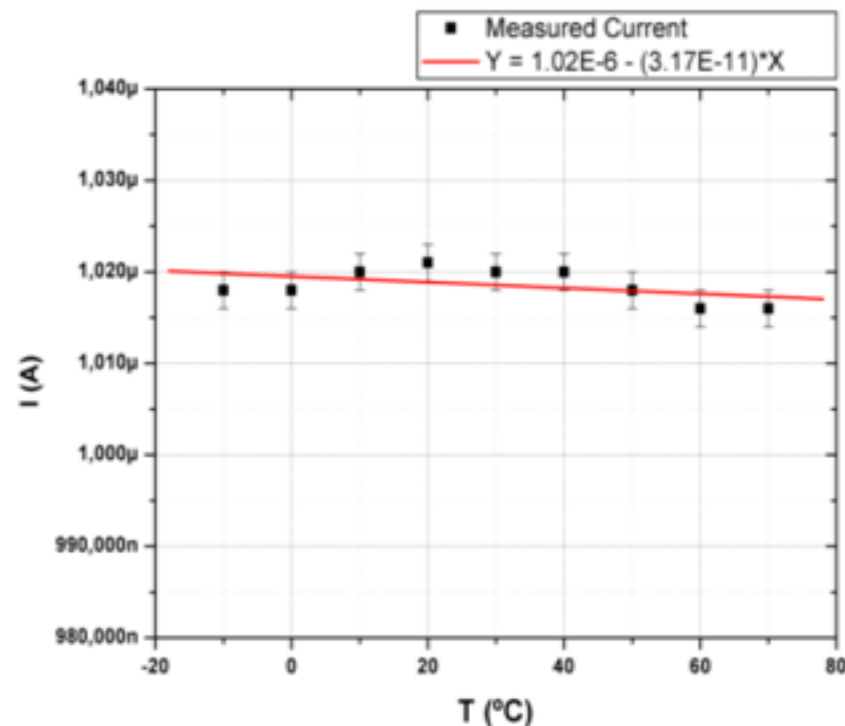
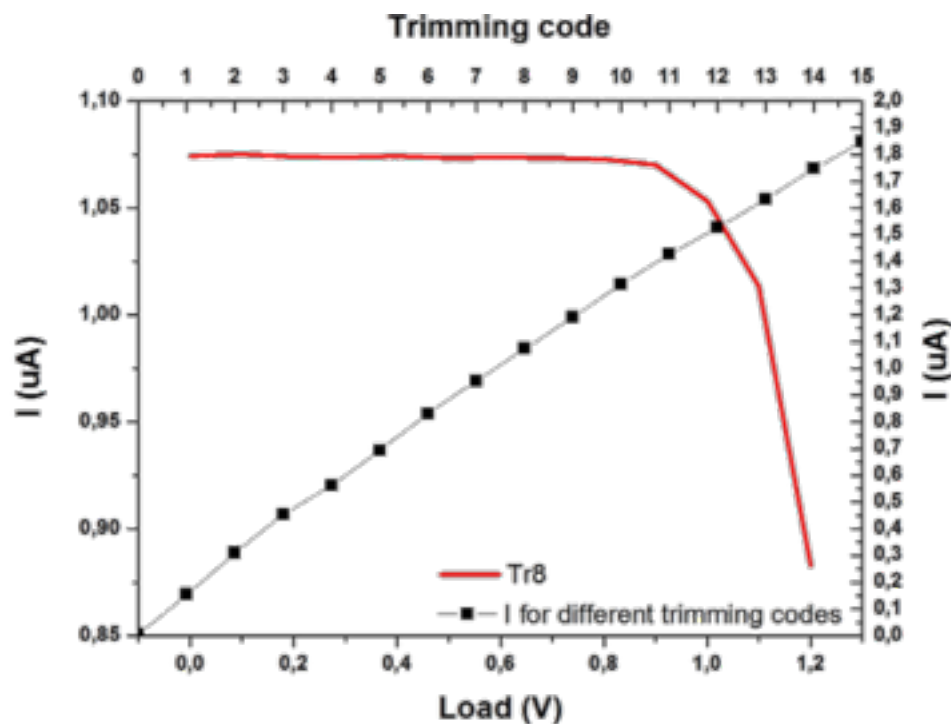
ANALOG BLOCKS

Analog Blocks – Current Reference (1uA)

Bias module provides 8 bias current to PLL, CML, and LDVS (each 1-255 uA with 8-bit DAC).

The core is Temperature Independent Current Reference (1uA)

- Compliance ✓
- Trim functionality ✓
- Temperature sensitivity ✓

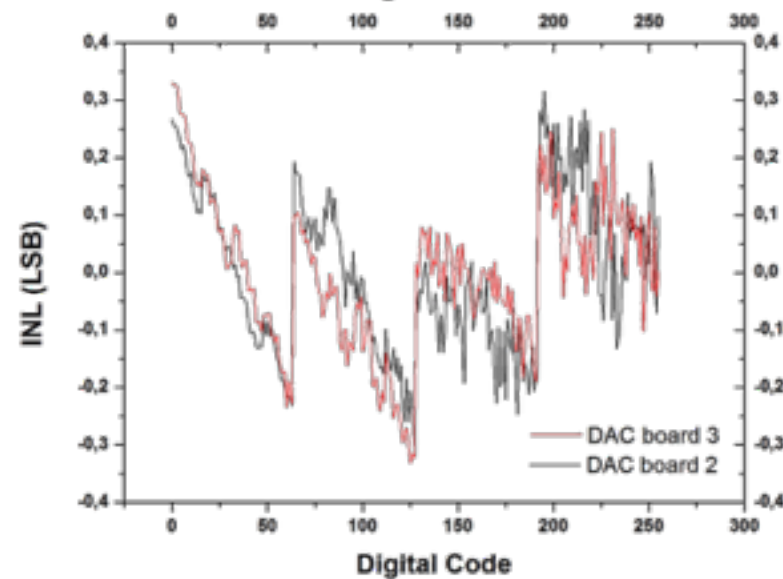
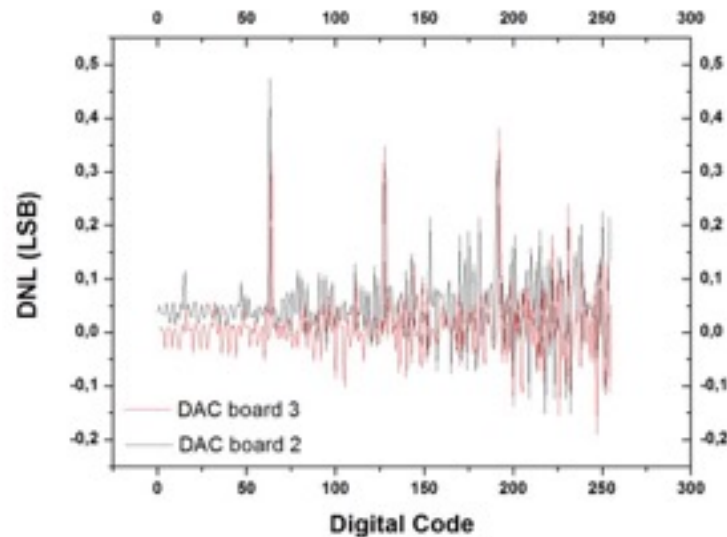
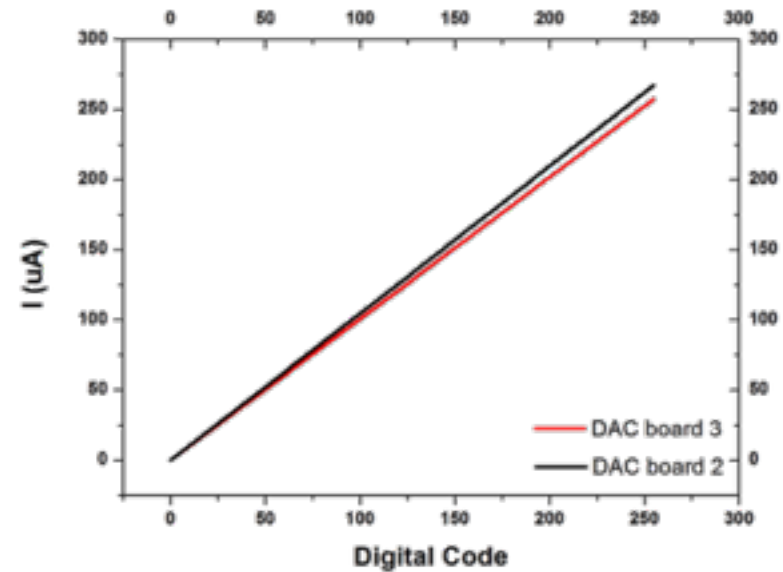


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Analog Blocks – 8-bit DAC

8-bit DAC for bias current control (1-255 μA)

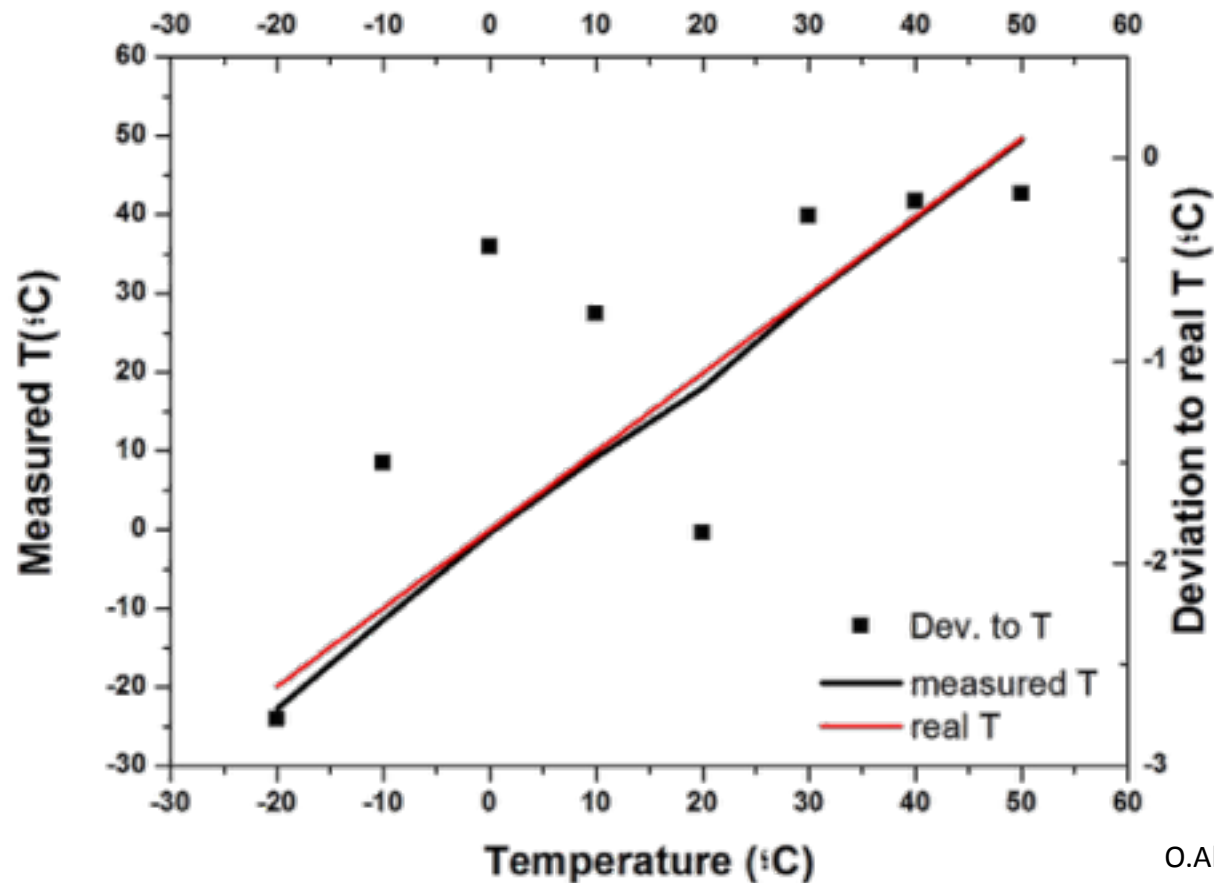
- Dynamic range ✓
- Linearity ✓



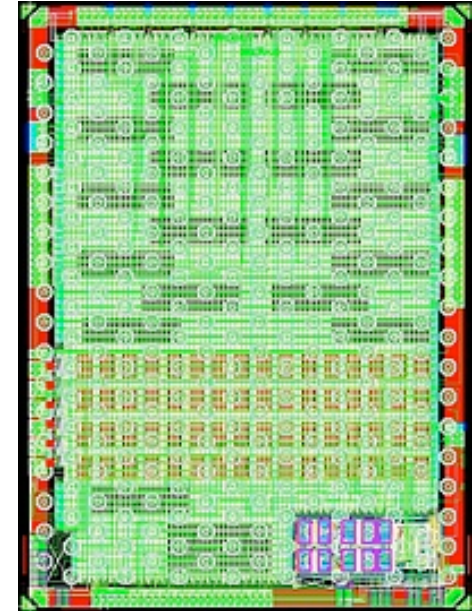
Analog Blocks – Temperature Sensor

Internal or external sensing diode + 16 bit Sigma-Delta ADC

- Measurement range $-20^{\circ}\text{C} \dots +60^{\circ}\text{C}$ ✓
- Accuracy $\pm 1^{\circ}\text{C}$ ✓



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DHPT 1.0

KNOWN ISSUES & LAYOUT IMPROVEMENT

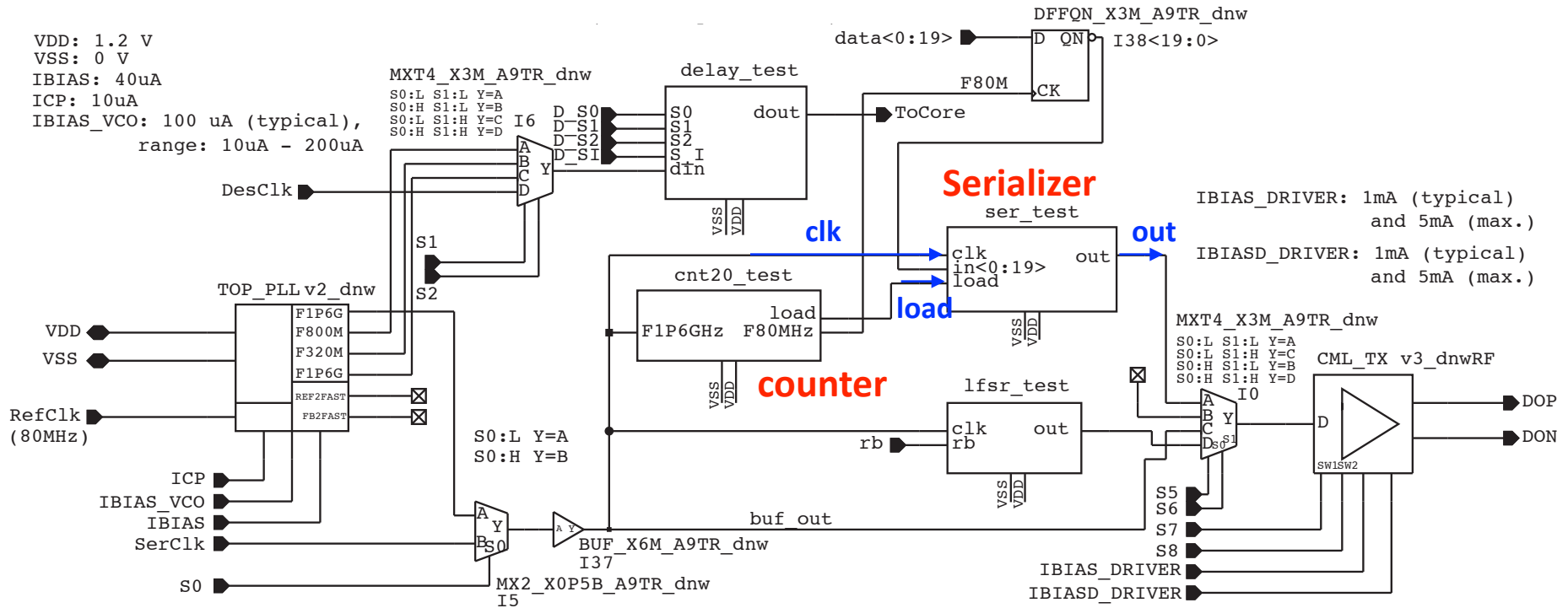
- ✓ Serializer behaviors
- ✓ CML output swing

- Serializer works, but VDD and/or GCK have to be adjusted:
 - GCK= 80 MHz → VDD= 1.6V (works but should not be applied for a long time)
 - GCK= 60 MHz → VDD = 1.4V (ok)
- Manufacturer test data → wafer batch has „slow NMOS“ (too high threshold)

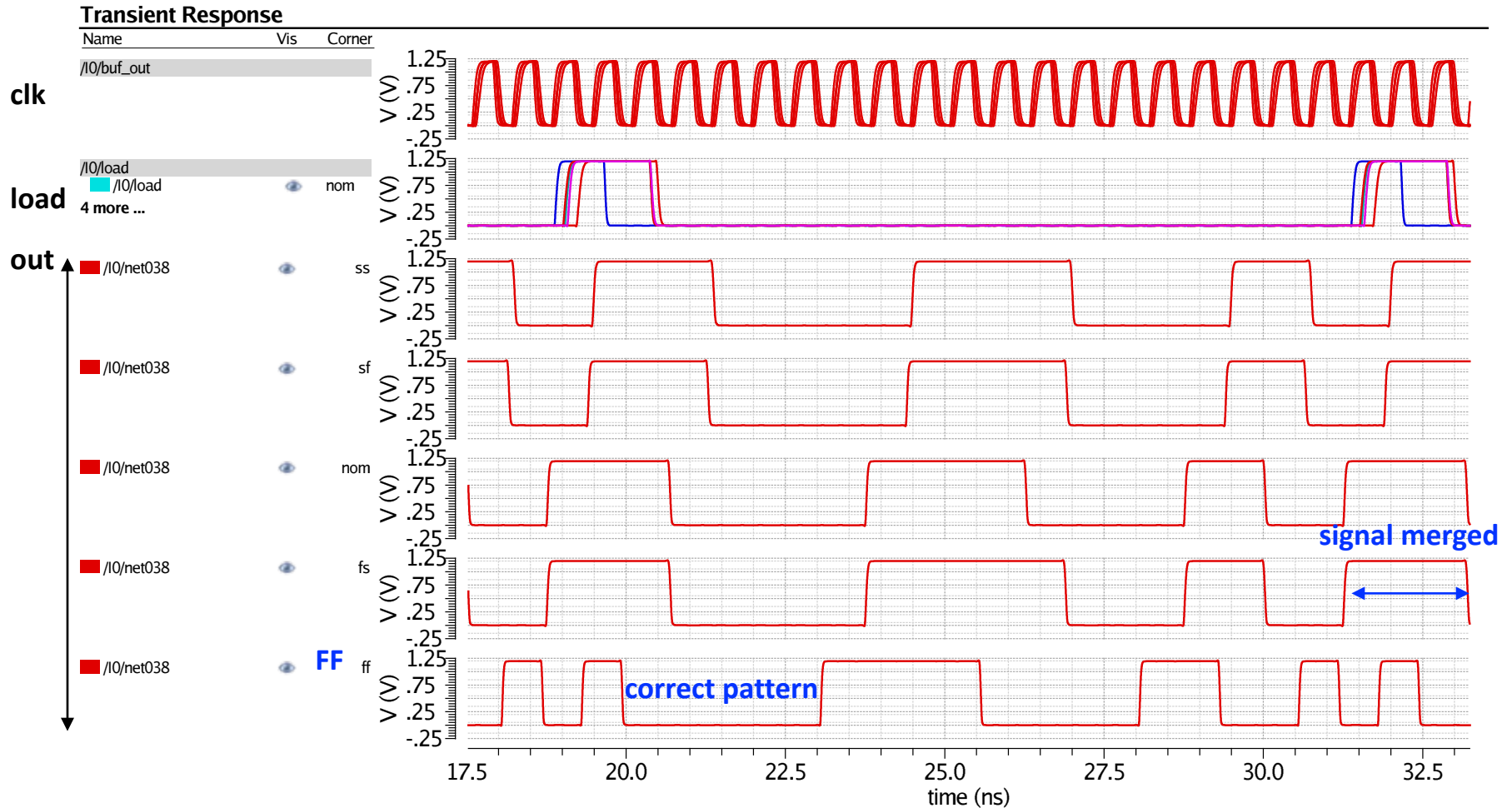
PARAMETER BY LOT:		SPEC LO	SPEC HI	MIN	MAX	MEAN	STD DEV
VT1_N4	(N/.3/.06/1)	0.300	0.490	0.368	0.490	0.423	0.029
Isof_N4	(N/.3/.06/1)	-1.400E-07	0.000	-8.958E-10	-3.833E-11	-2.339E-10	2.063E-10
Isat_N4	(N/.3/.06/1)	0.491	0.735	0.547	0.673	0.593	0.031

- Issue within the Serializer localized → can be fixed with a small design change

Schematic of the serializer

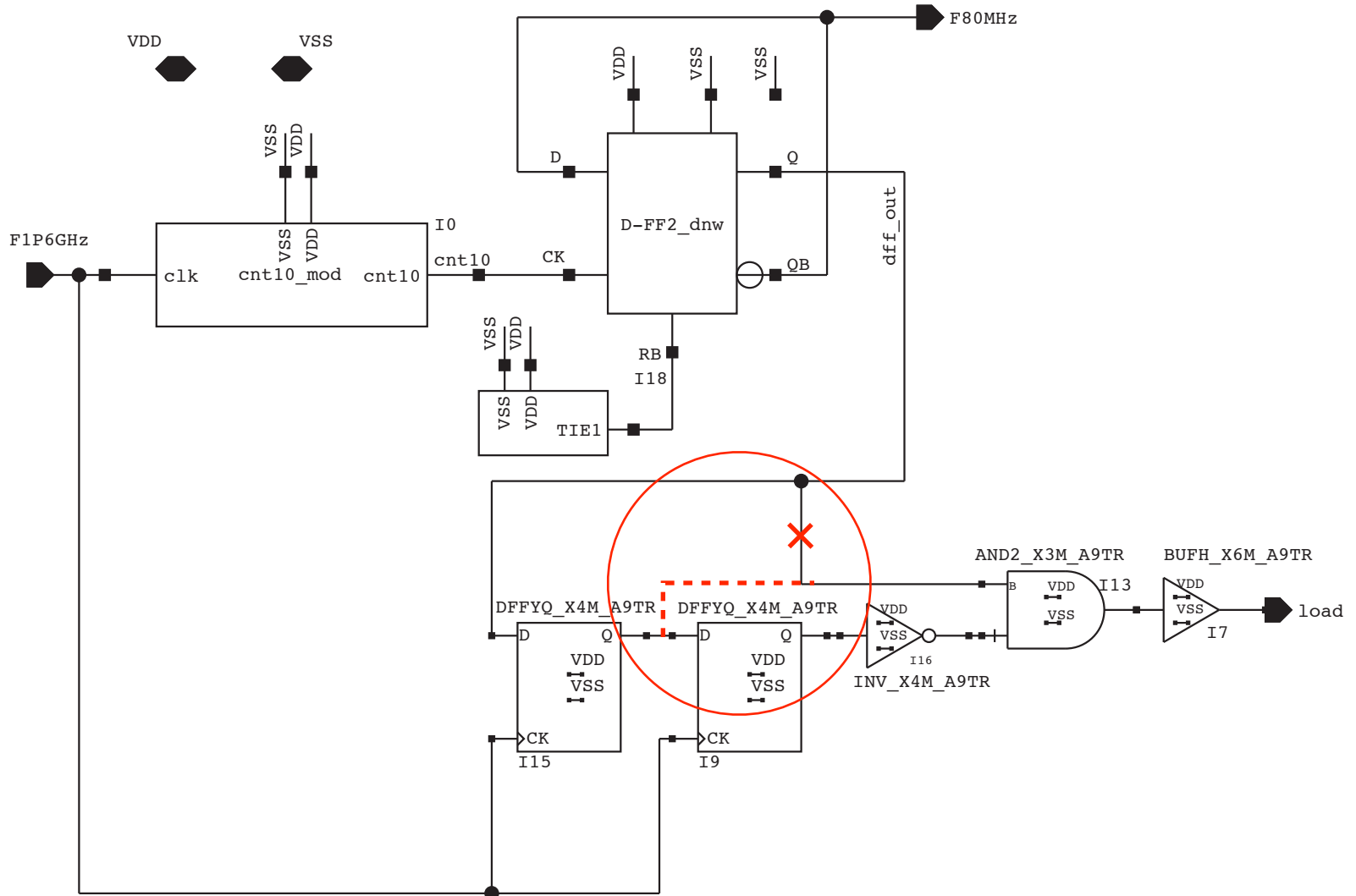


Simulation result

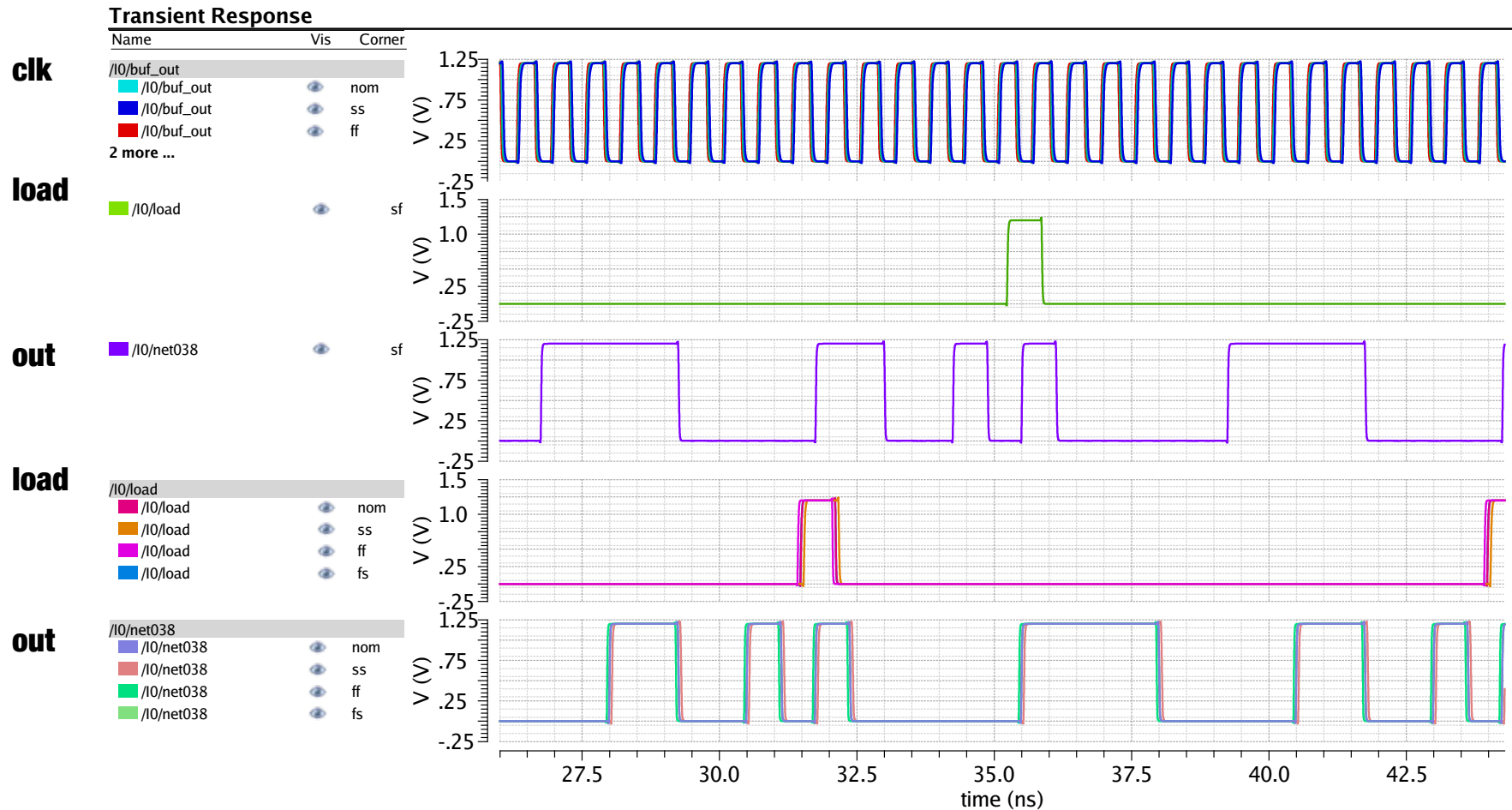


Timing of "load" is not provided correctly, except fast-fast corner.

counter circuit



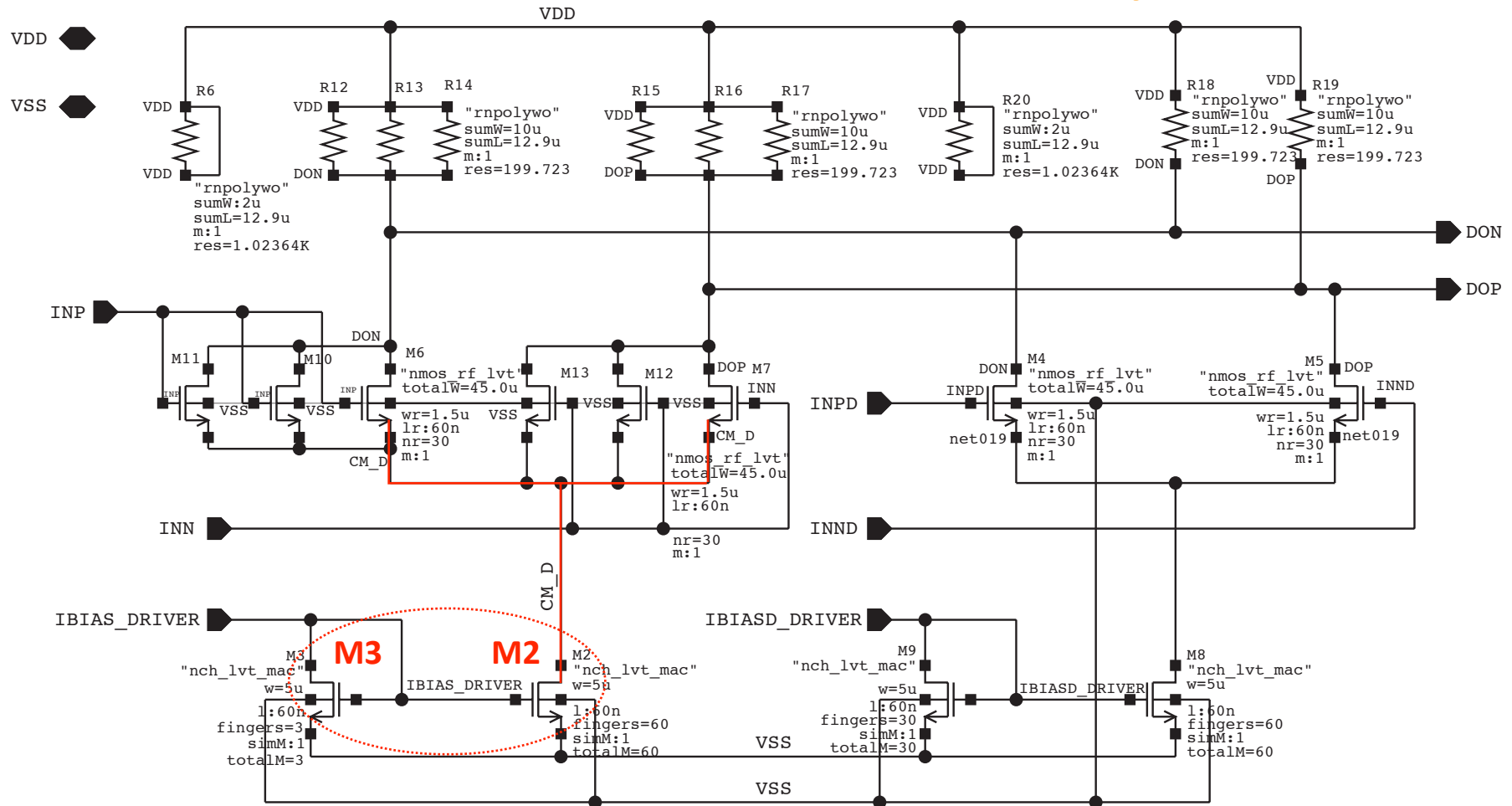
Simulation result (after modification)



Correct pattern can be obtained in all corners.

Schematic of the CML driver

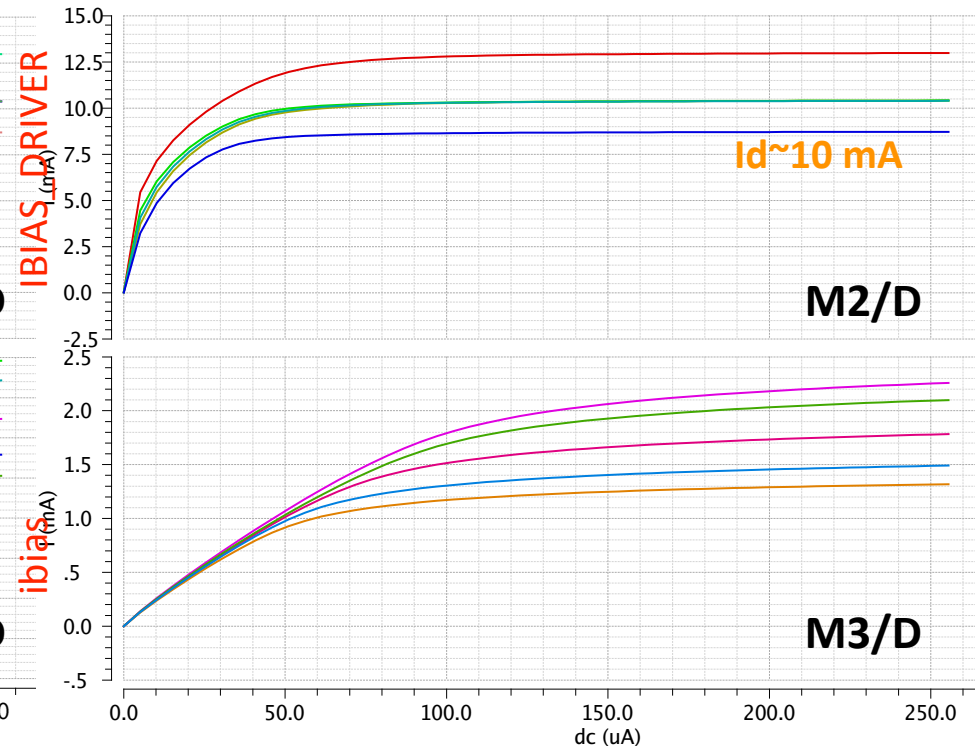
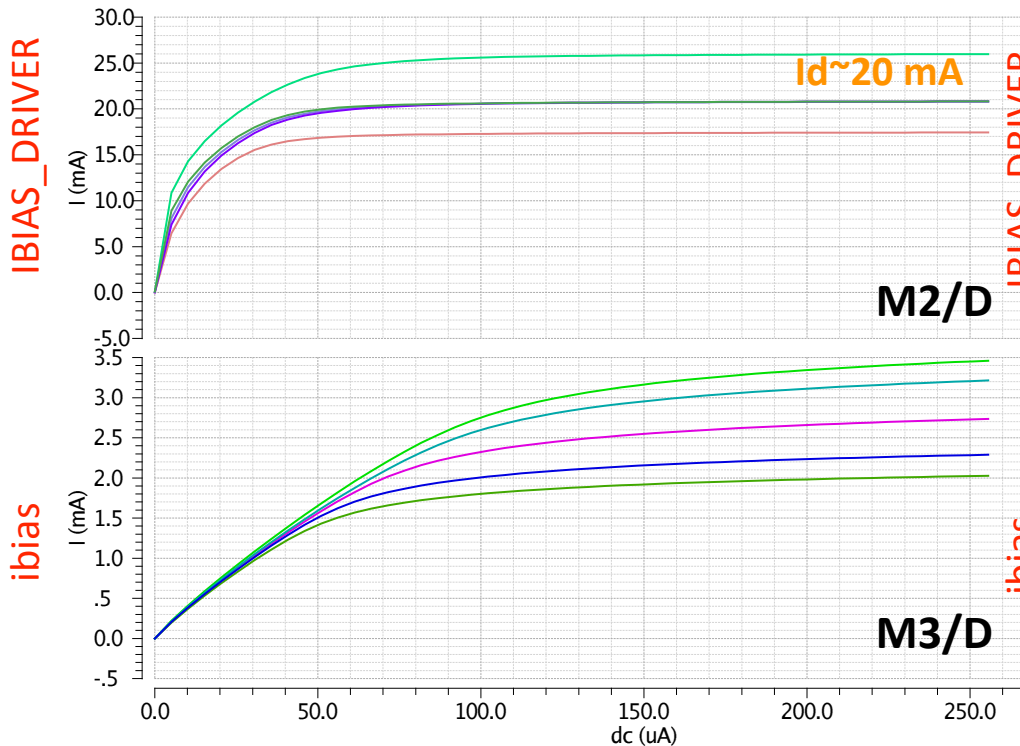
M2 is out of saturation with smaller bias current than expected.



without any output connection

Schematic simulation (ideal)

After parasitic extraction (realistic)

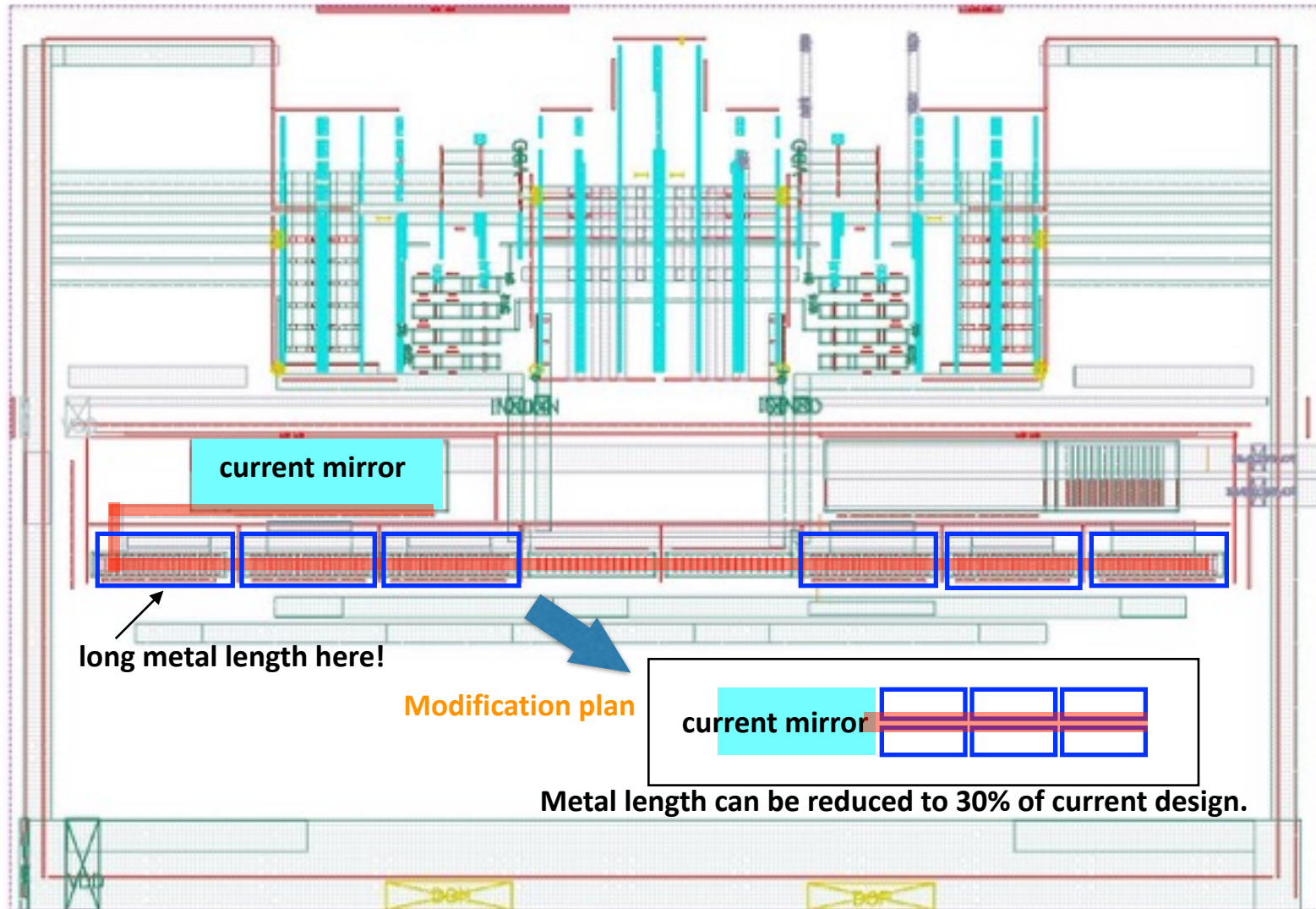


The difference comes from “voltage drop due to large serial resistance” between current source and switching transistor.



Layout can be improved in the next submission. The ideal output swing is two times larger.

Modification plan



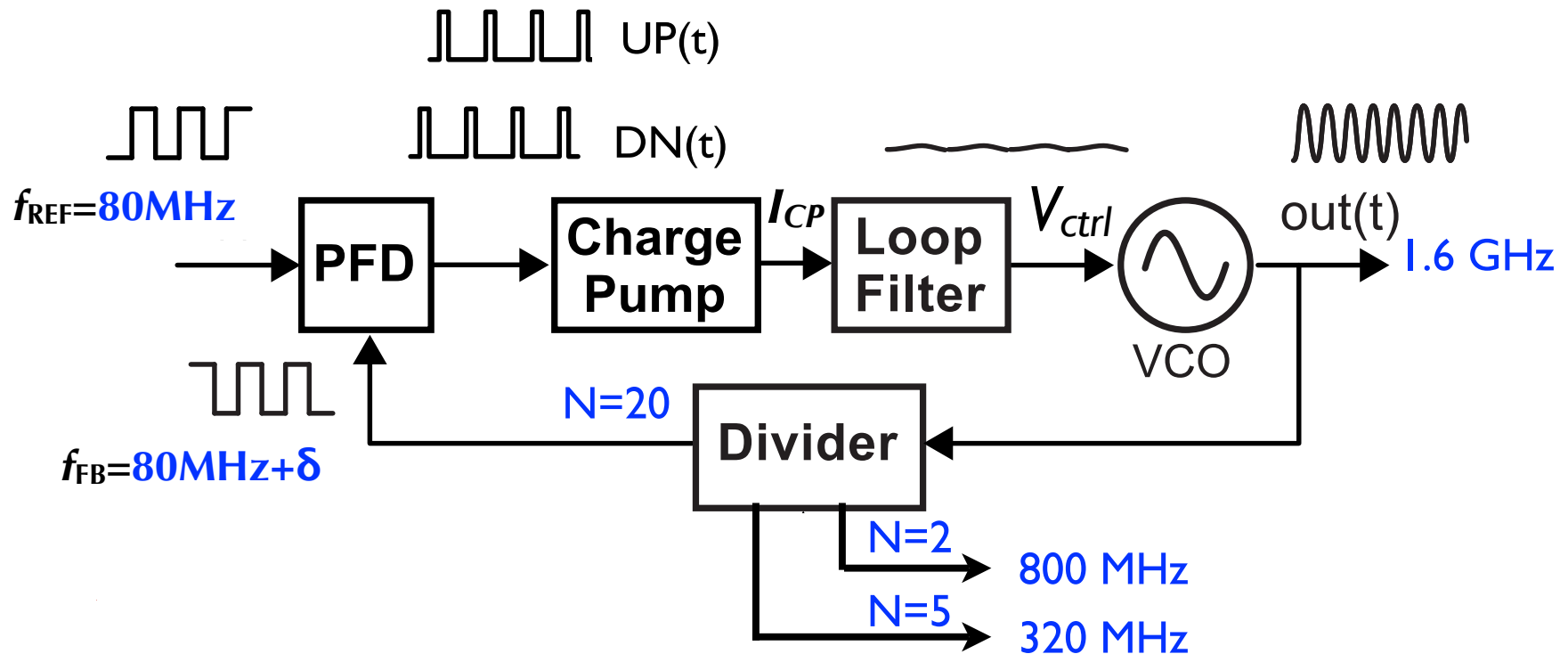
Thank you very much.

SCHEMATIC DETAILS (BACKUP)

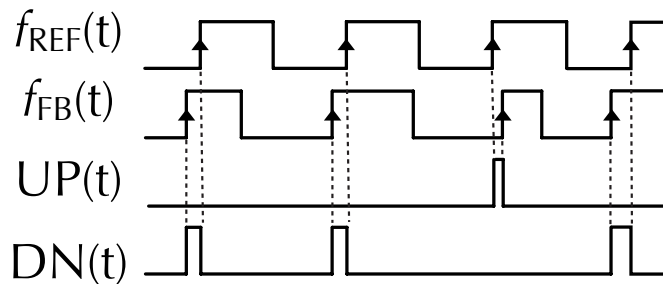
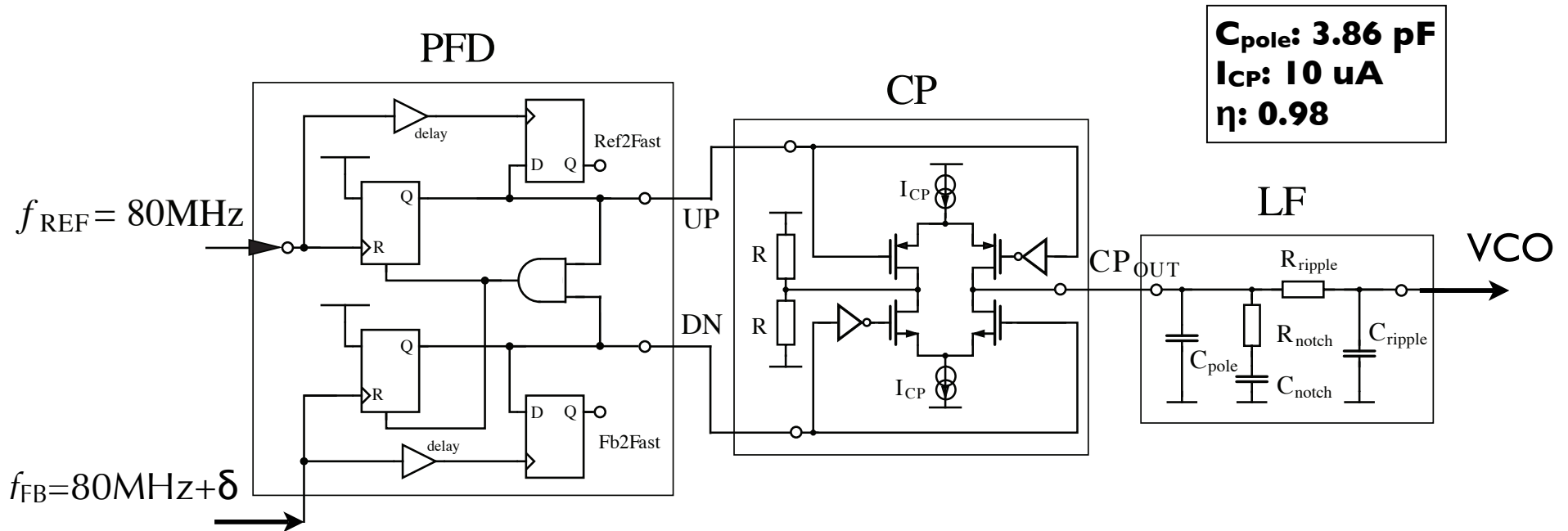
Overview of PLL architecture

PLL generates 1.6 GHz from 80 MHz reference clock.

- ◆ Voltage Controlled Oscillator (VCO) provides oscillating waveform with variable frequency
- ◆ PLL synchronizes VCO frequency to input reference freq. through feedback
- ◆ Use digital counter structure to divide VCO frequency



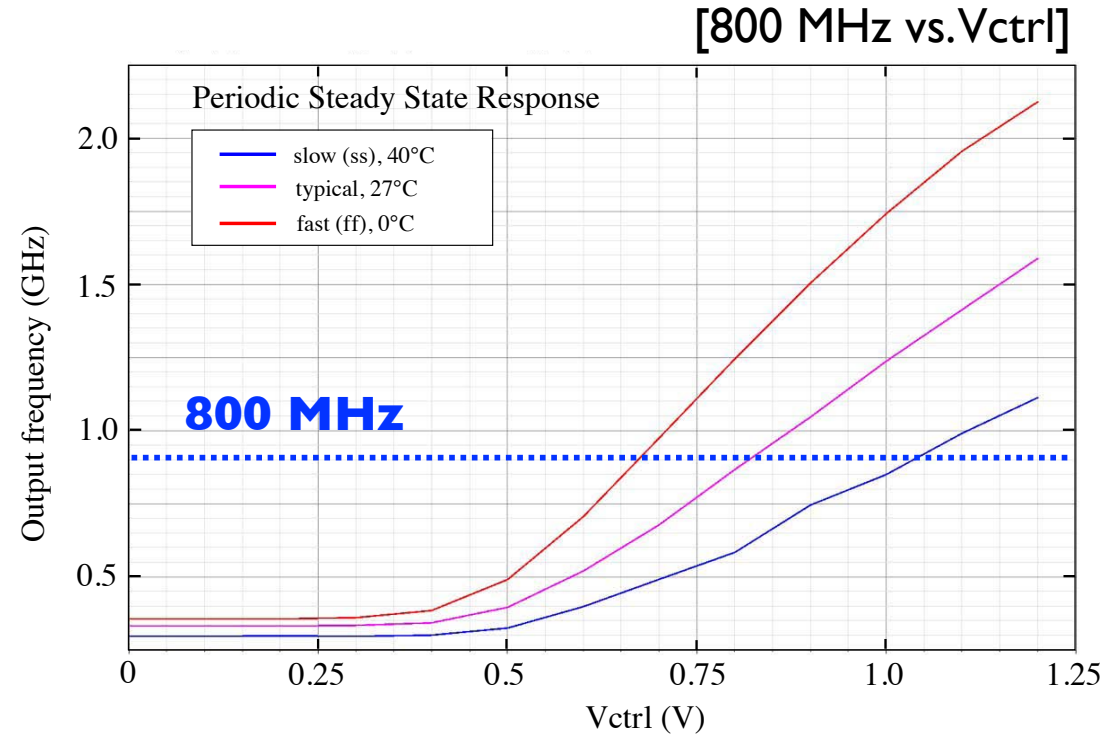
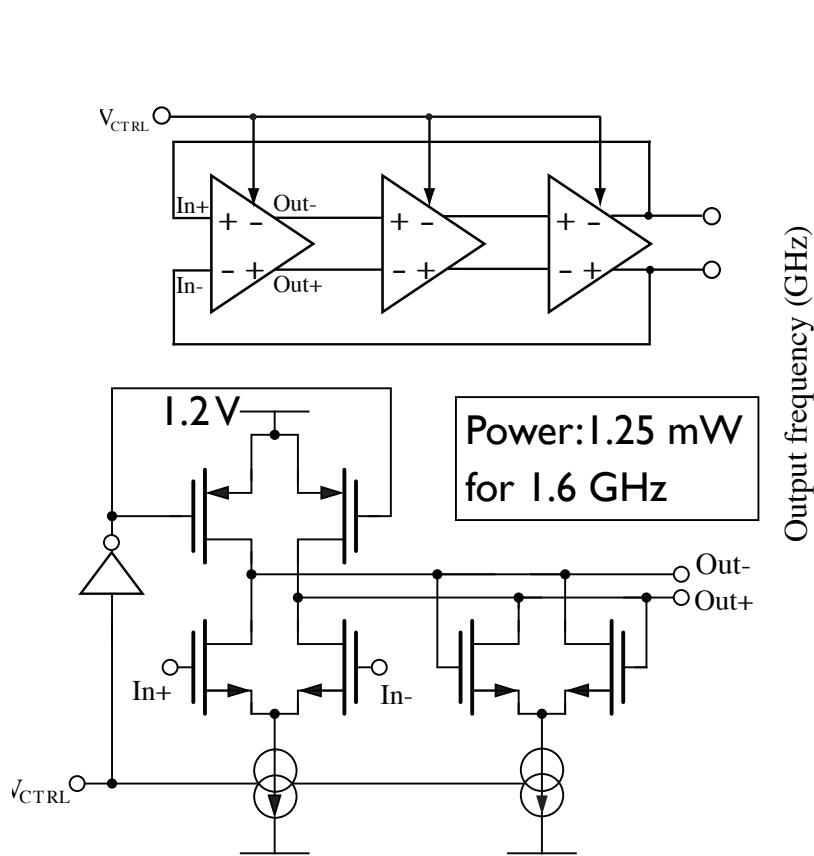
PFD, Charge pump, and Loop filter



- ◆ Phase-Frequency Detector (PFD): classical two flipflops structure, additional error detection circuit
- ◆ Charge-pump (CP): differential structure with dummy branch
- ◆ Loop-filter (LPF): MIM structures, well-tuned parameters for PLL stability

Voltage-Controlled Oscillator (VCO)

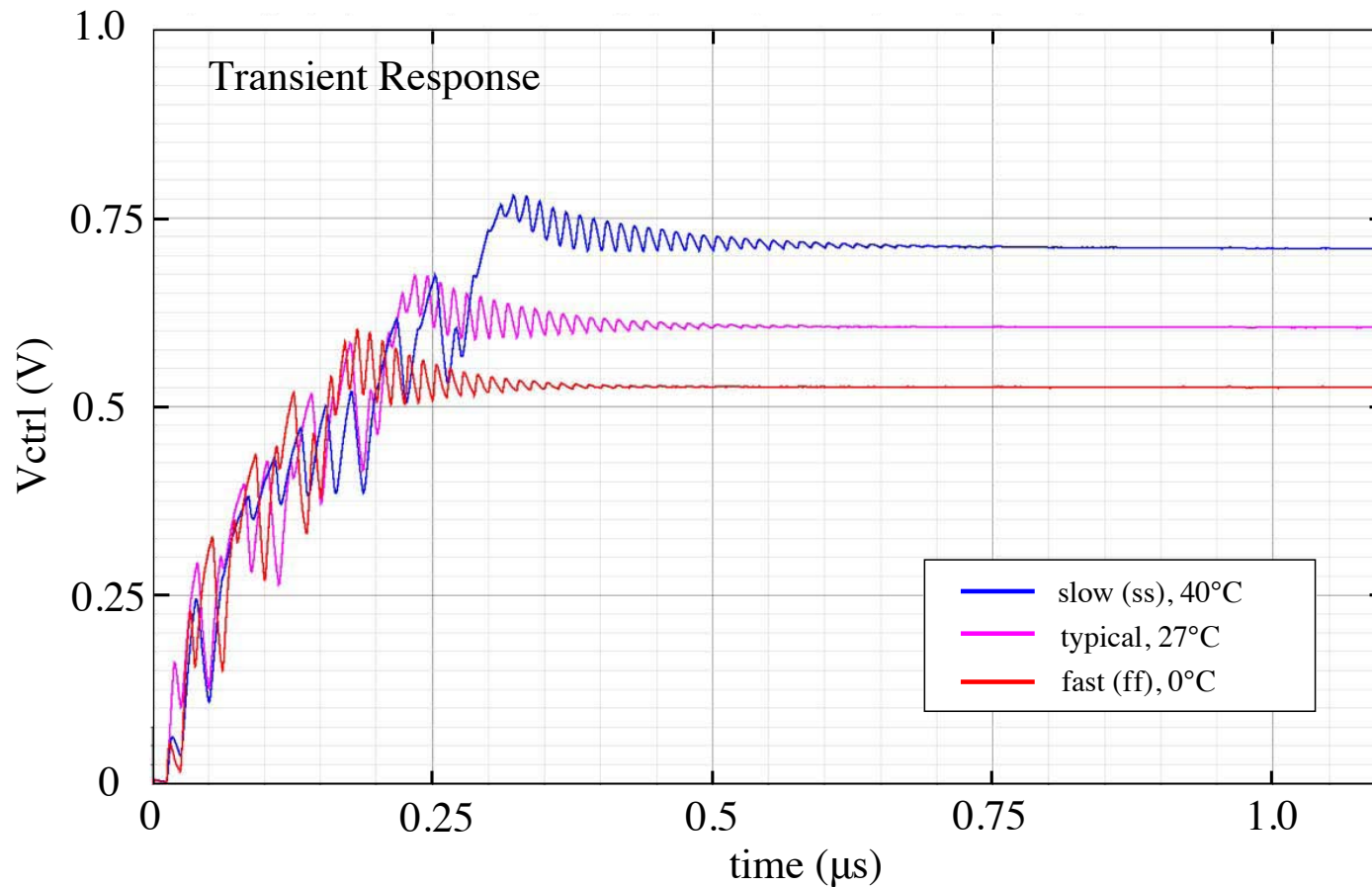
- ◆ three inverters connected as a ring oscillator
- ◆ differential pairs with PMOS loads with cross-coupled stages for rail-to-rail switching



- ◆ wide tuning range of the output frequency
- ◆ oscillation freq. of 1.6 GHz is secured under 3σ process variations.

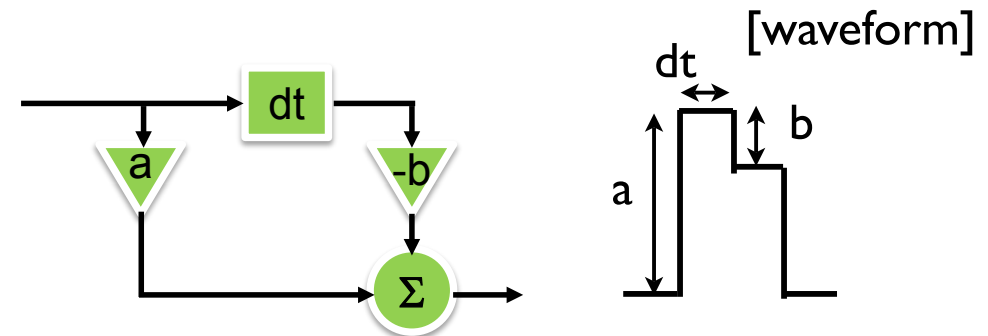
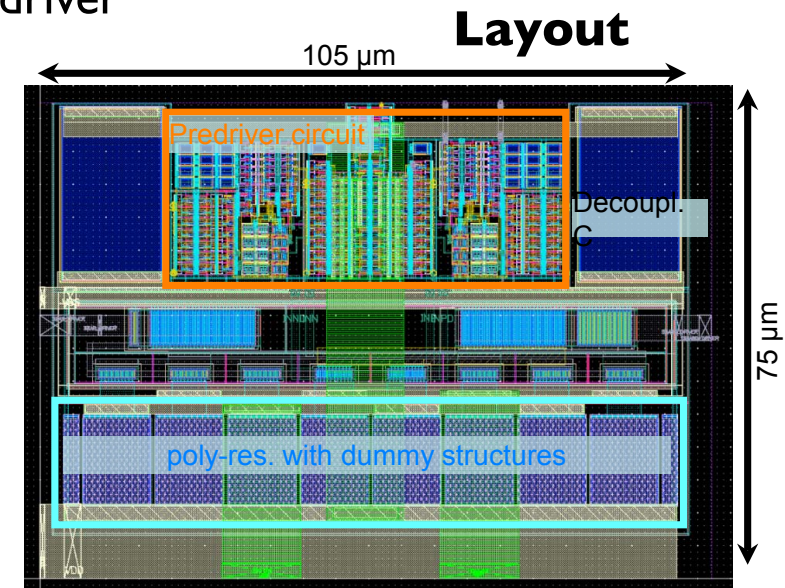
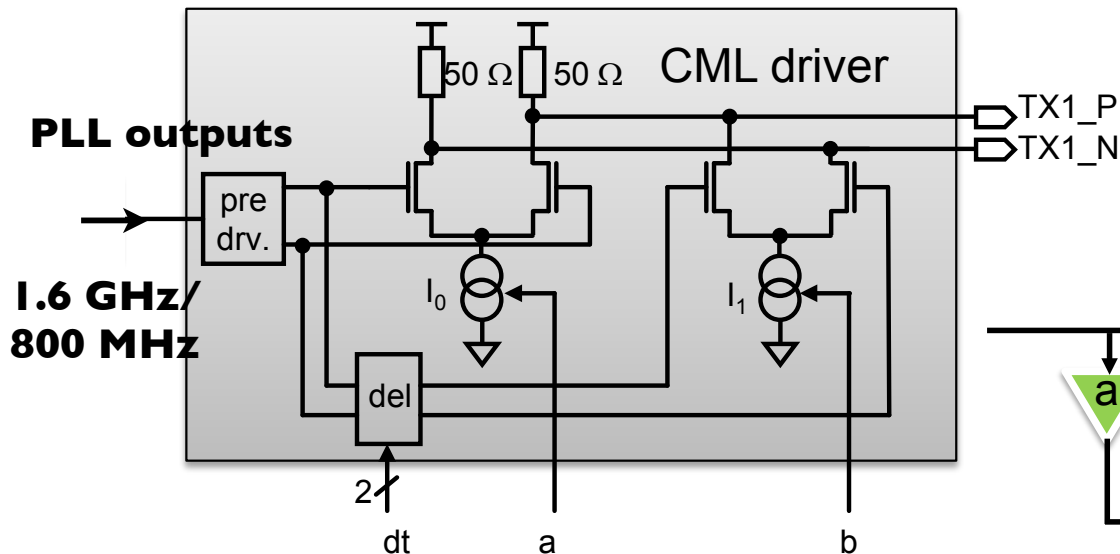
PLL Settling Behavior

- ◆ The V_{ctrl} settles to the final value in $t_{settle} \sim 750$ ns within accuracy of 2%.
- ◆ Stable behavior for all process corners.
- ◆ Layout parasitics are included in the simulation.

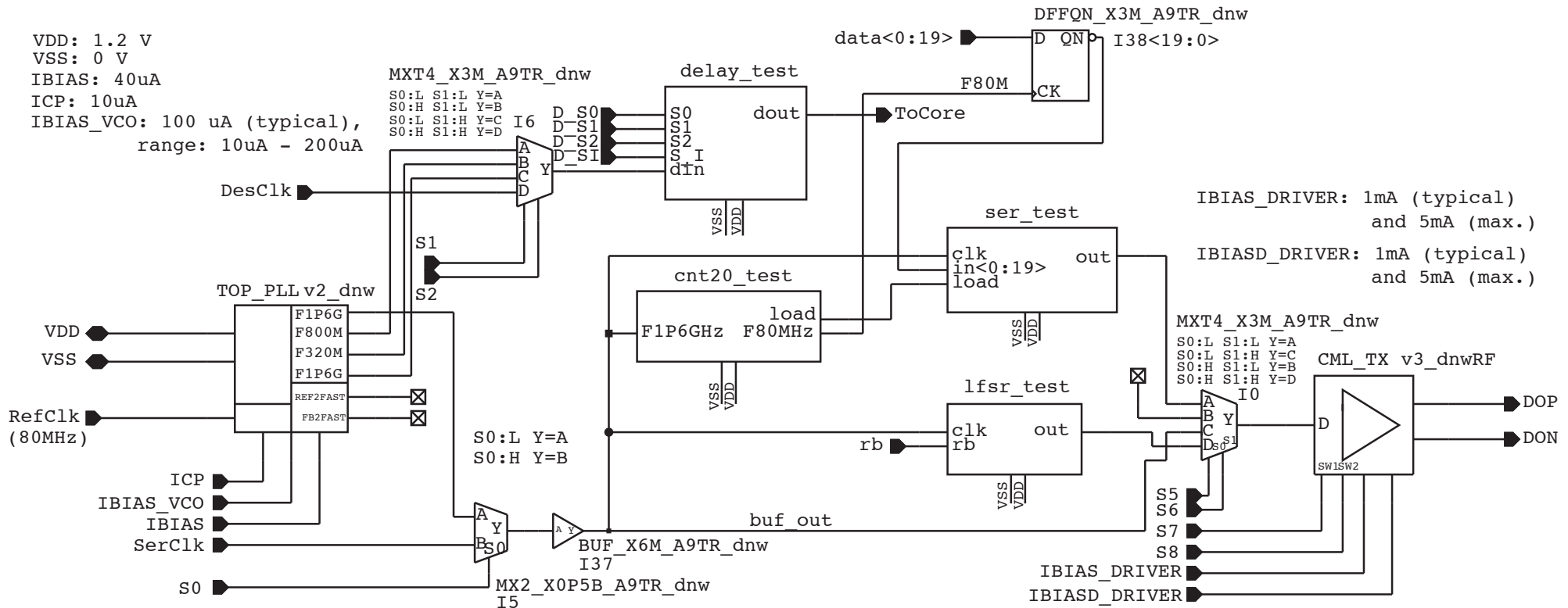


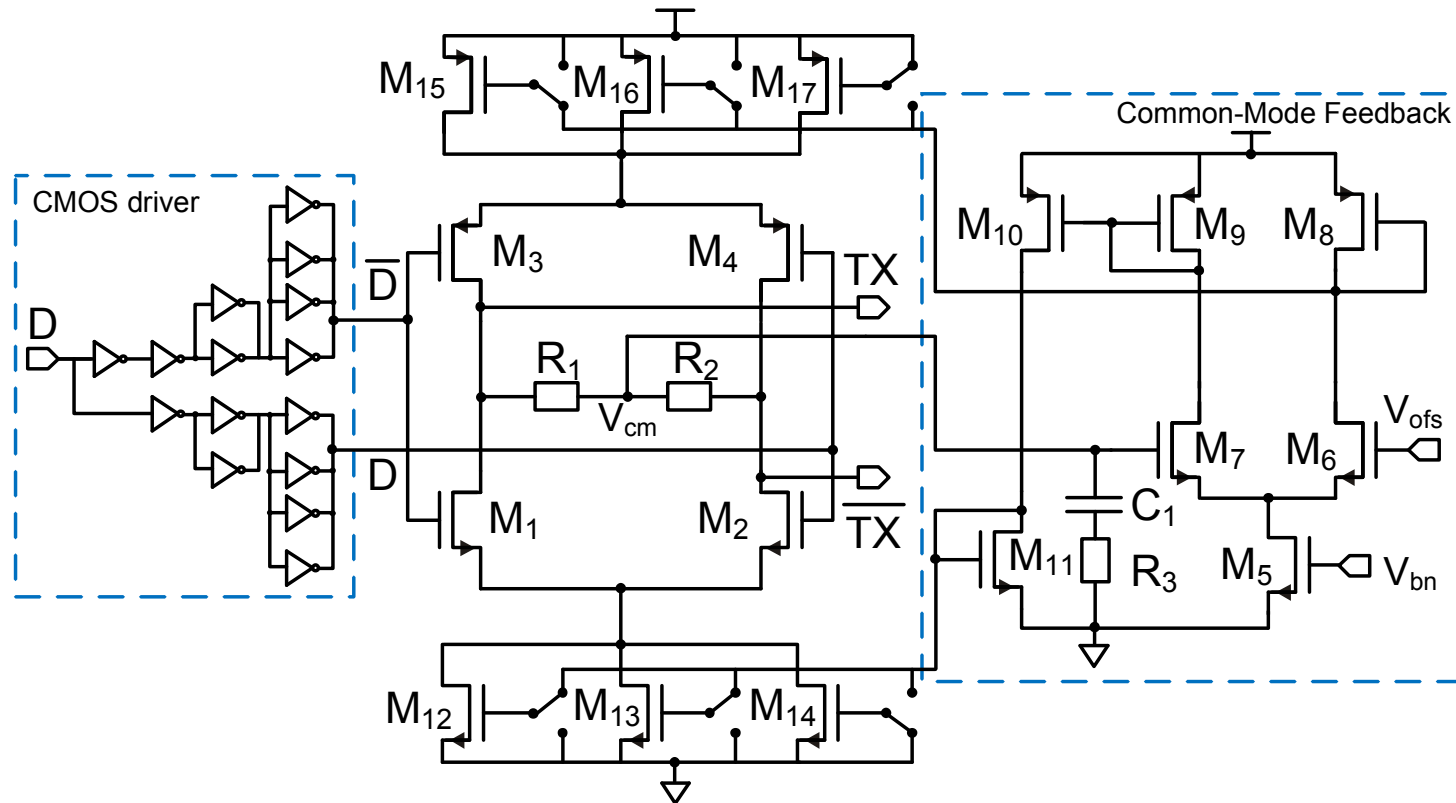
CML driver with pre-emphasis

- ◆ Differential current mode logic (CML):
driver (phase control) + differential pair post driver
- ◆ Two differential pairs: adj. bias currents:
 - tap weights (a & b),
 - delay (dt) upto 600ps with 4 fixed steps
- ◆ Dummy poly layout for impedance matching

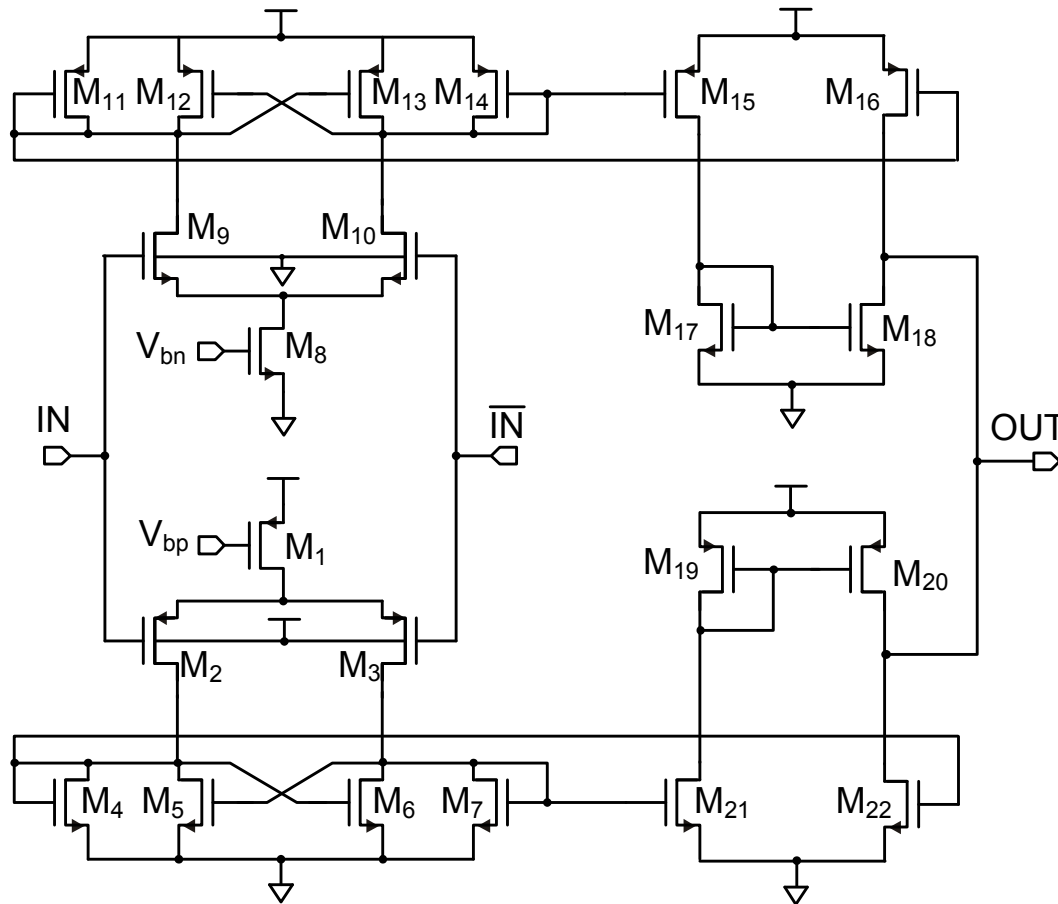


PLL+Serializer+CML





- ✓ four switching transistors with common-mode feedback circuit.
- ✓ adjustable signal current from 0.6—3 μA .
- ✓ 100 Ohm termination resistors are implemented with poly-resistors.

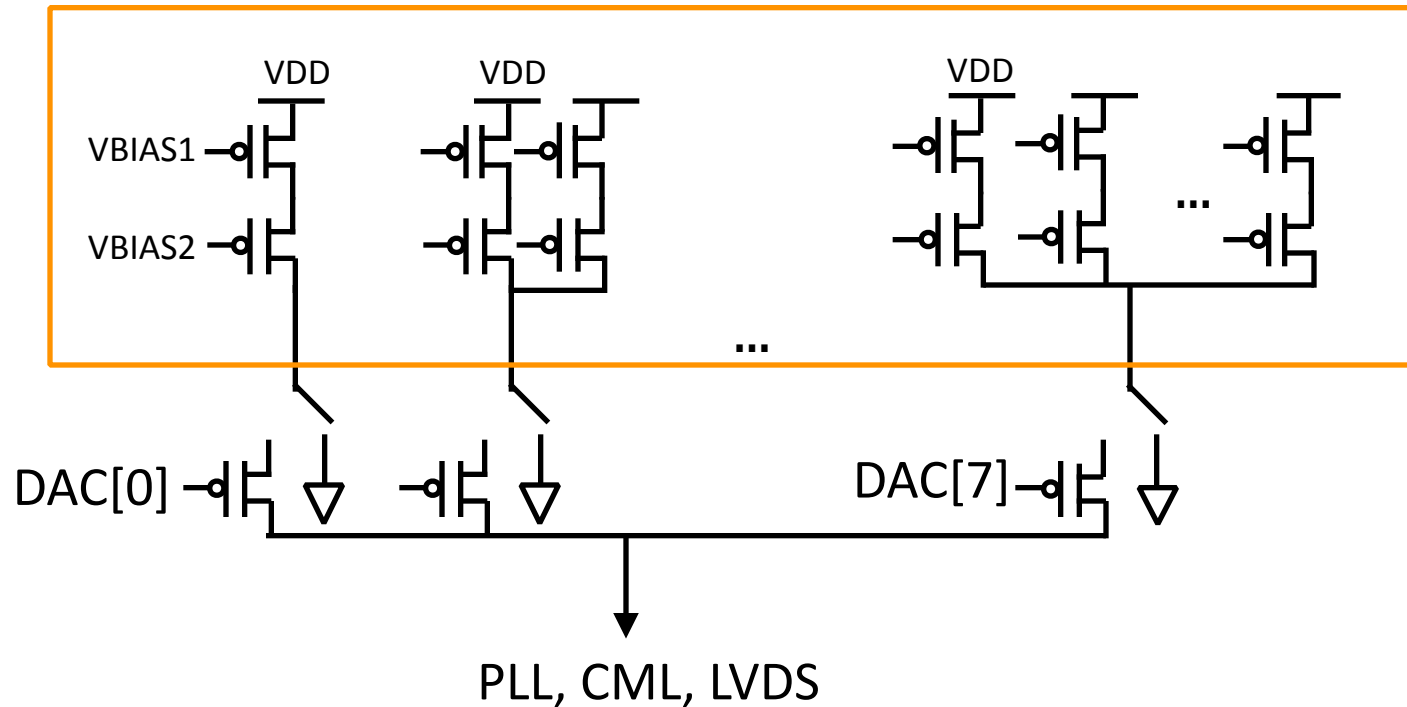


- ✓ NMOS & PMOS diff. pair for wide common-mode input range
- ✓ positive feedback circuit M4~M7, M11~M14 for higher speed and hysteresis.
- ✓ high-gain 2nd-stage amp. for full CMOS output

It provides 8 bias currents to PLL, CML, and LVDS.

An 8-bit current-steering DAC provides a programmable current (1 to 255 μA).

binary weighted DACs 1-256 μA



Temperature sensor (designed by UB)

- ✓ Operating temperature of $-20^{\circ}\text{C} \sim 70^{\circ}\text{C}$, with $\Delta T = 0.2^{\circ}\text{C}$ accuracy.
- ✓ based on Voltage Proportional To Absolute Temperature (VPTAT) method.
- ✓ drop voltage of the diode is digitalized by $\Sigma\Delta$ -ADC and temperature.

